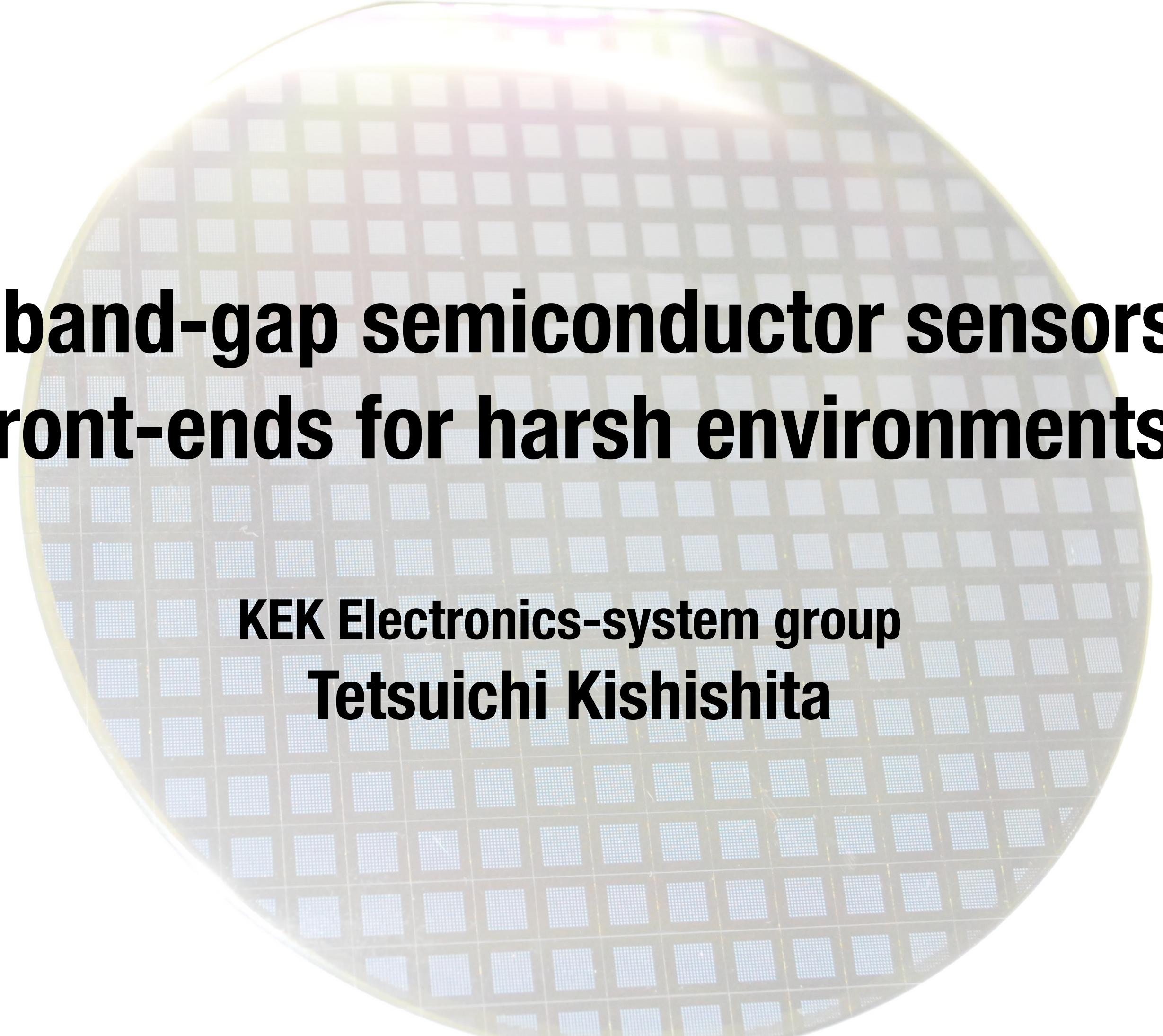


Wide band-gap semiconductor sensors and front-ends for harsh environments



KEK Electronics-system group
Tetsuichi Kishishita

Outline

- SiC sensors for MIP detectors at COMET muon experiment @ J-PARC (Japan Proton Accelerator Research Complex)
 - Application to muon beam monitor and proton extinction monitor
 - Characteristics of the PN-sensors
- Diamond sensors for neutron detection at Fukushima nuclear power plant
 - Device fabrication and characteristics
 - Detector system and prototype performance

Introduction

- SiC and diamond are more radiation-hard than standard n-type Si, 10^{14} n_{eq}/cm^2 for SiC and 10^{15} n_{eq}/cm^2 for diamond.
- Uniform device characteristics and productivity are still challenging.

Property	Diamond	GaN	4H-SiC	Si	Ge	CdTe	CdZnTe
E_g [eV]	5.5	3.39	3.26	1.12	0.67	1.44	1.60
$E_{breakdown}$ [V/cm]	10^7	4×10^6	2.2×10^6	3×10^5	10^5	TBD	TBD
μ_e [cm^2/Vs]	1800	100	800	1450	<3900*[2]	1090*[1]	906*[3]
μ_h [cm^2/Vs]	1200	30	115	450	<1900	110	-
v_{sat} [cm/s]	2.2×10^7	-	2×10^7	0.8×10^7	0.74×10^7 *[5]	10^7	10^7
Z	6	31/7	14/6	14	32	48/52	48/52/30
ϵ_r (dielectric const.)	5.7	9.6	9.7	11.7	TBD	TBD	TBD
e-h energy [eV]	13	8.9	7.6-8.4	3.6	2.9	4.5	5.0
Density	3.515	6.15	3.22	2.33	5.3	5.9	5.8
Displacem. [eV]	43	20	25	13-20	15-18	5.3-6.2*[4]	-

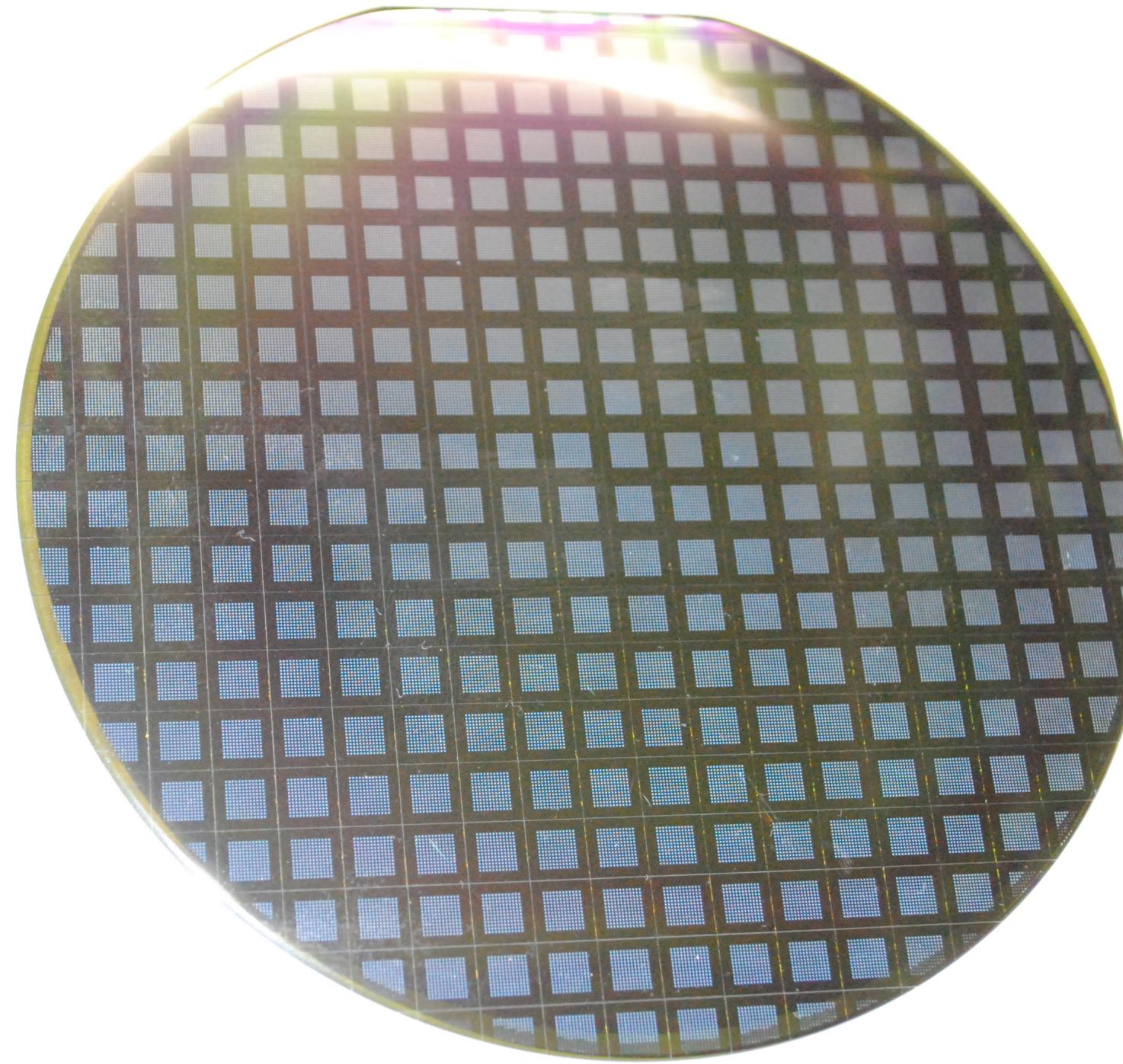
low leakage current

high radiation-tolerance small signal charges

For stable device production, KEK-Esys collaborates with AIST power device group from 2019.

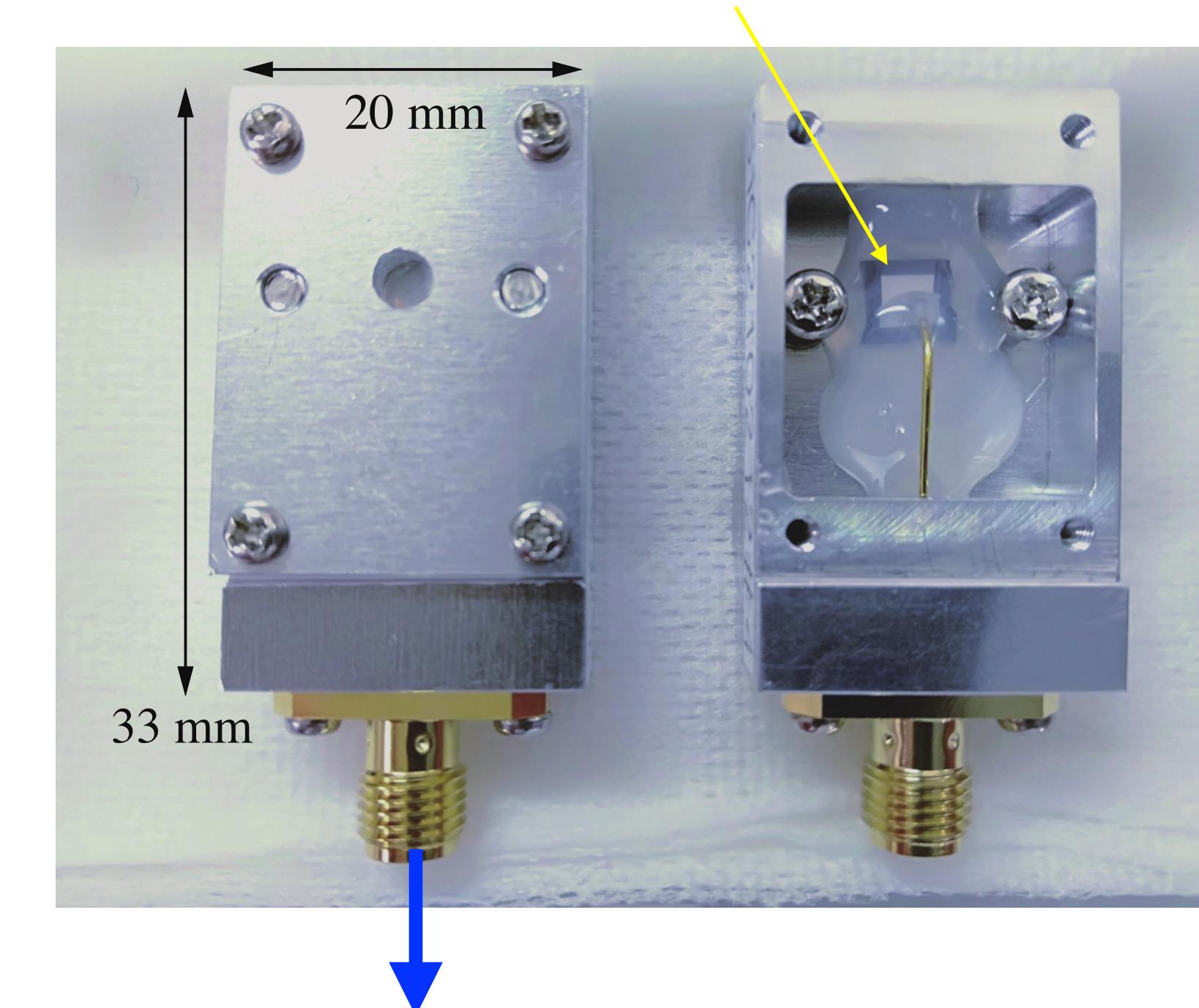
SiC device fabrication

- PN diodes in wafer process
- Reverse bias tolerance of 3 kV
- 50 um epi grown on (0001) 4H-SiC n-type substrate @AIST
- Nd-Na: $4.7 \times 10^{14} \text{ cm}^{-3}$
- Thickness: 350 um
- 260 dies with $5 \times 5 \text{ mm}^2$ from 4-inch wafer, $4 \times 4 \text{ mm}^2$ active area



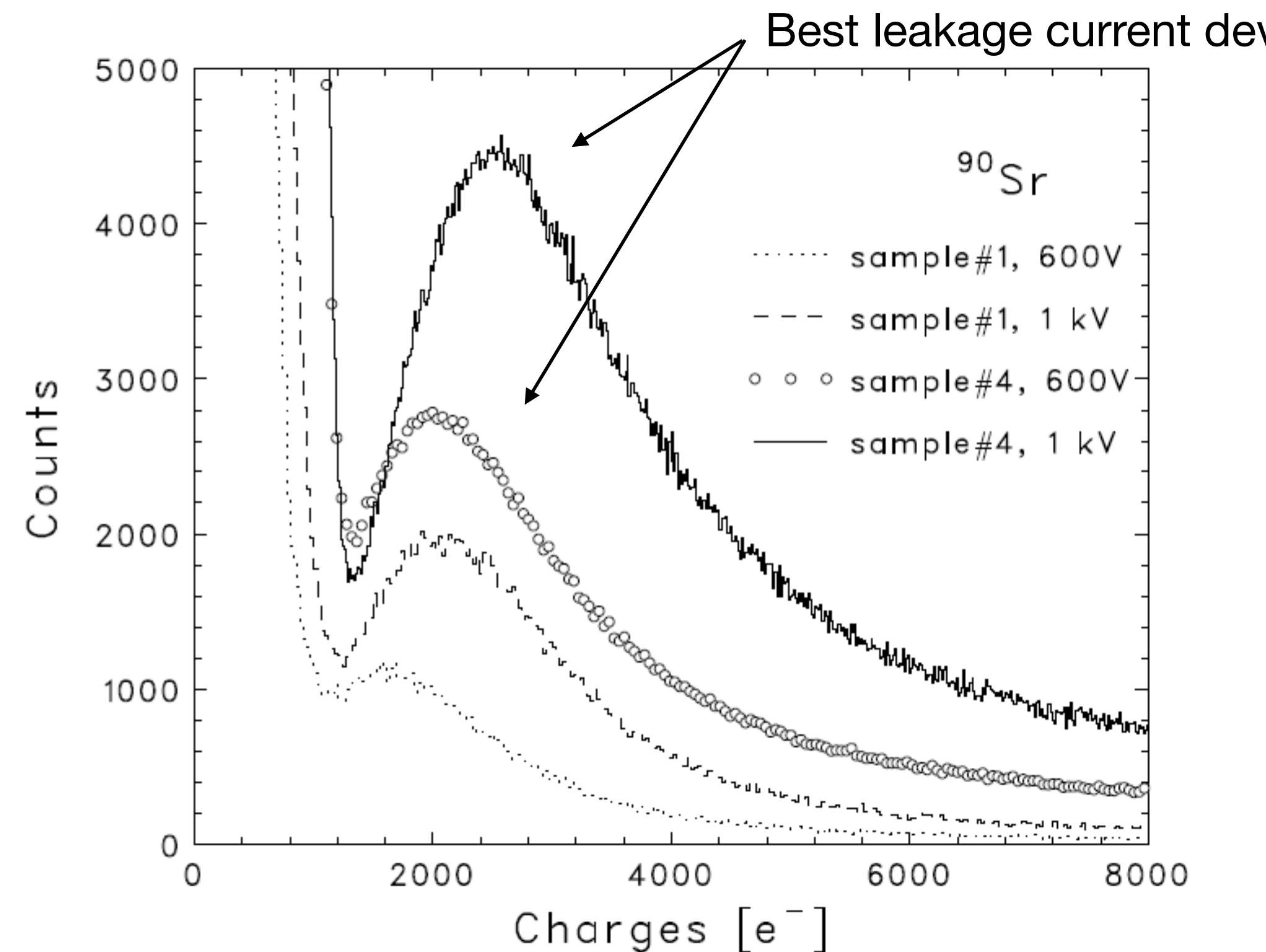
Schottky diode	PN diode
- Easy process	- Difficult process (High temperature annealing)
- Sensitive to surface conditions	- Less sensitive to surface conditions

Silicone rubber for preventing electric discharges

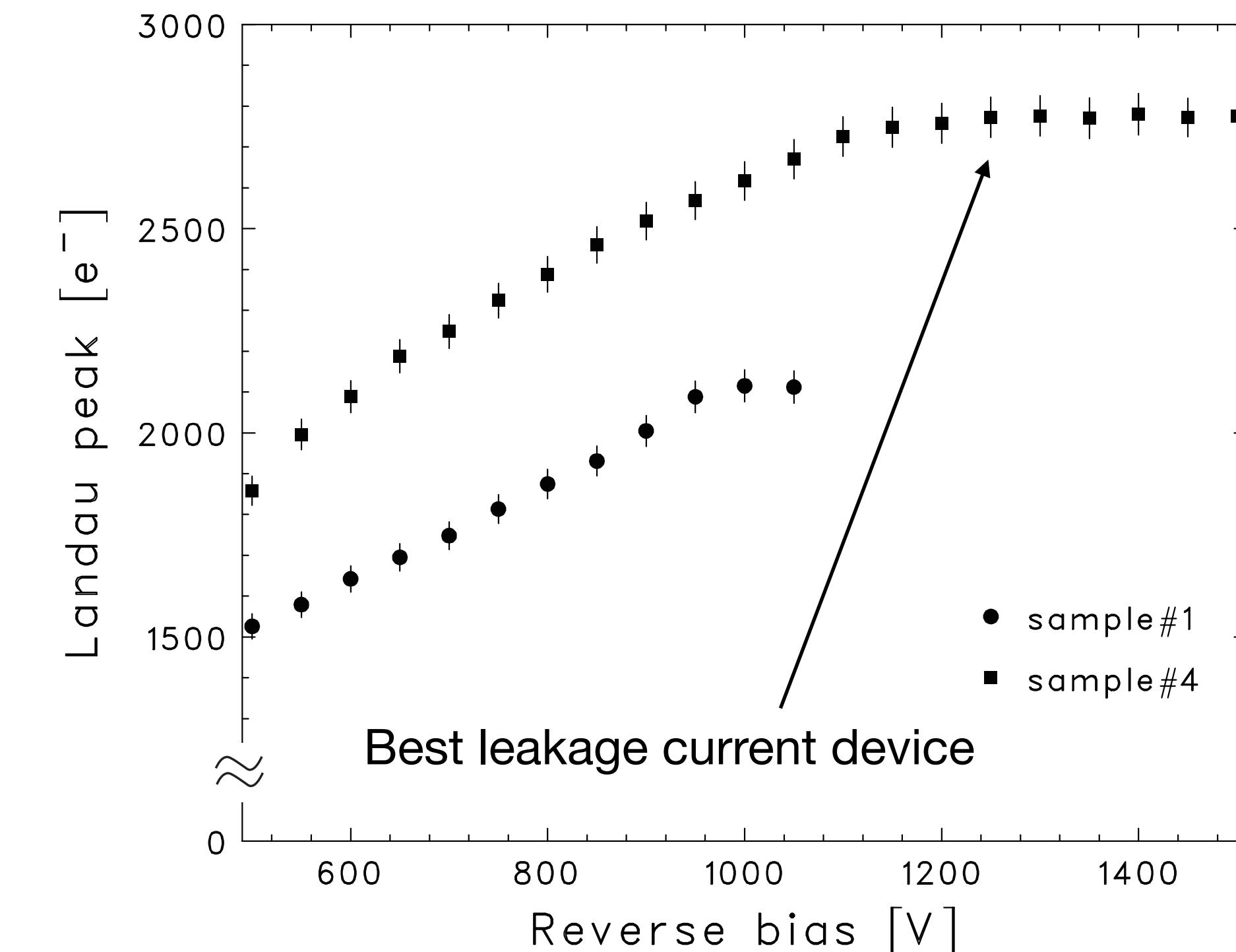


Device characteristics

- Leakage current <10 nA (26 samples from 260 dies), uniform within one order of magnitude
- Stable Landau peak position (no polarization/charge-up)
- Full depletion voltage 1000 V for 50 um epi (TCAD).



Landau peak is separated from pedestal in worst leakage device.

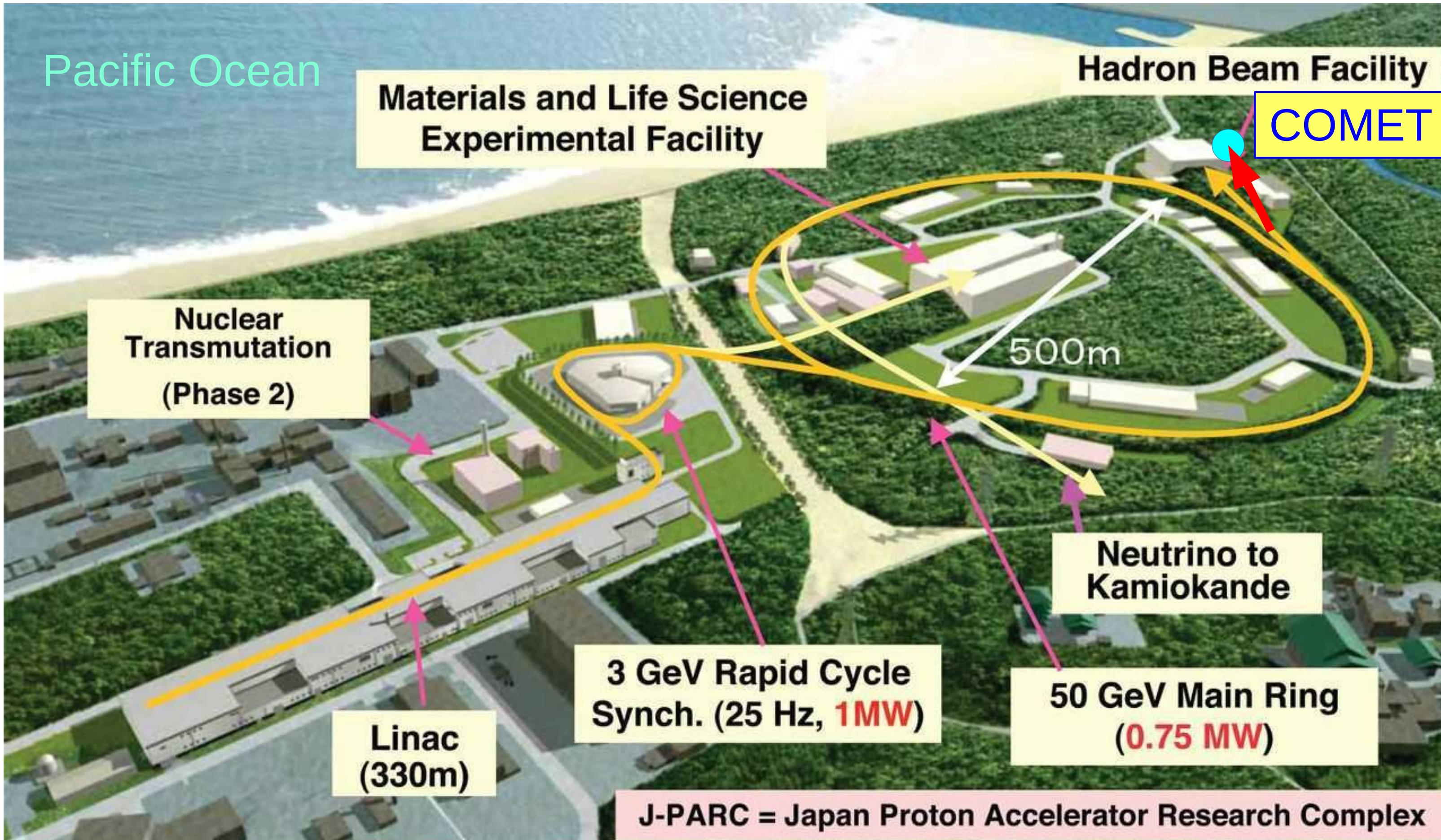


Full-depletion voltage is consistent with TCAD simulation.

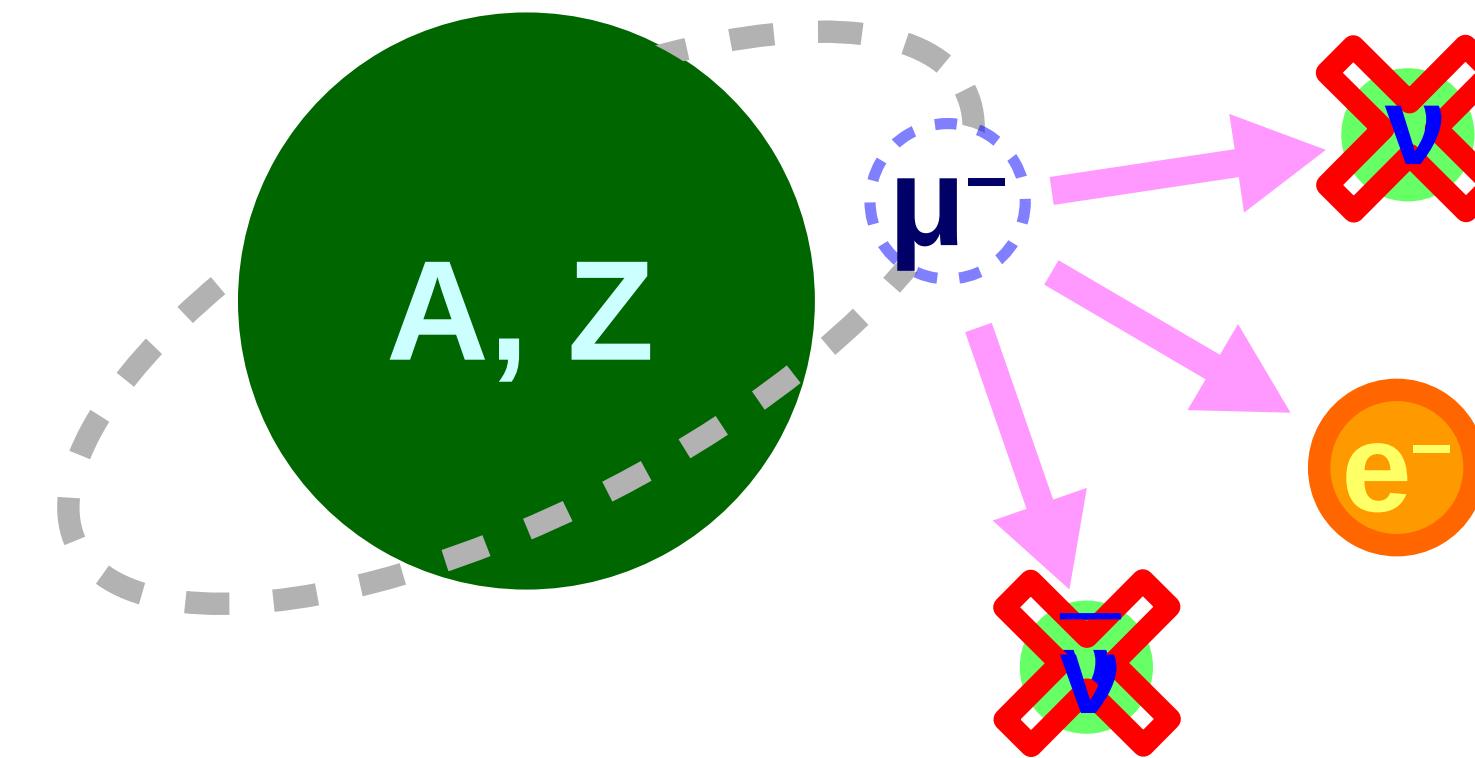
What can we do with these devices?

Needs for SiC sensor: COMET at J-PARC

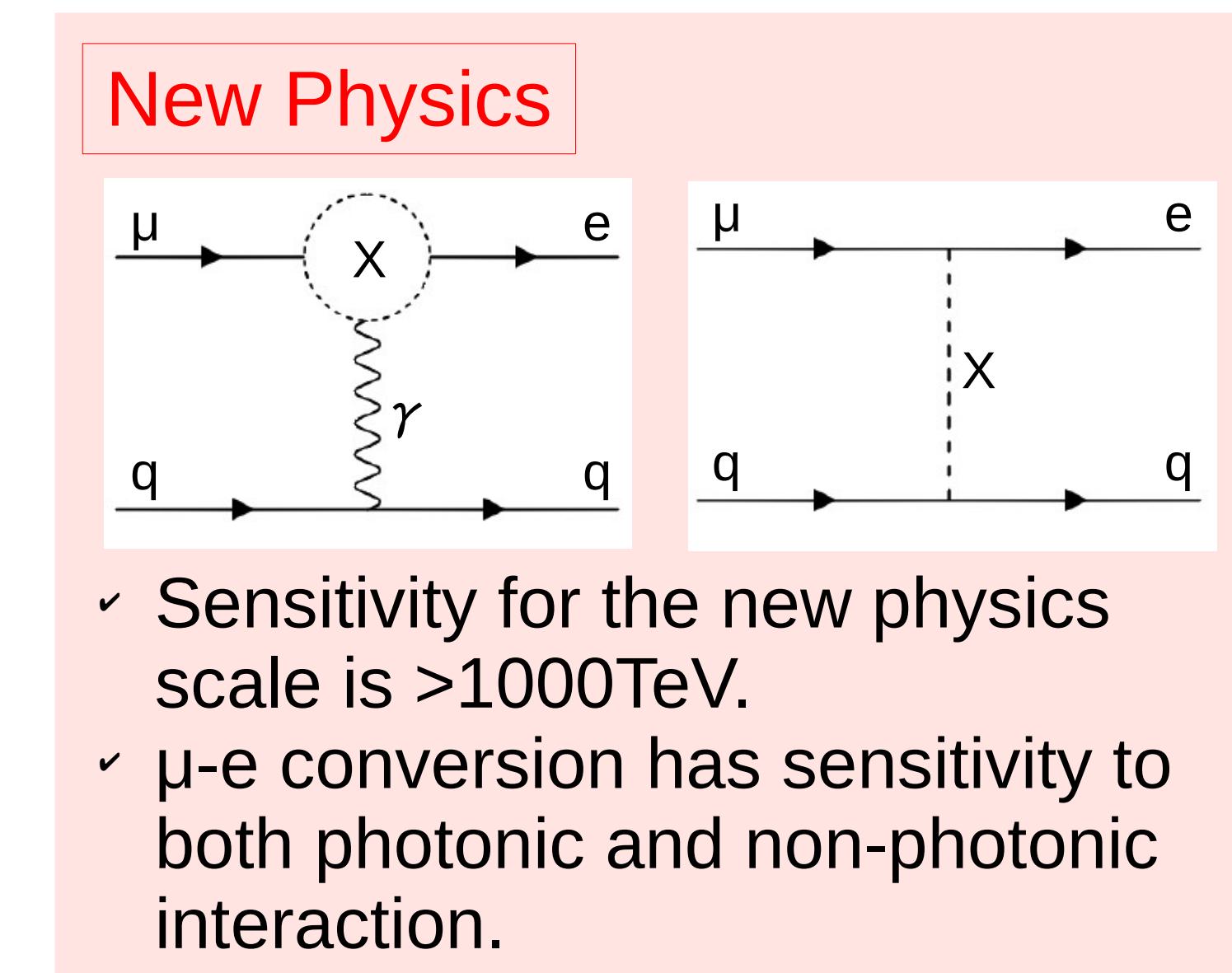
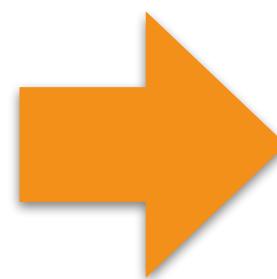
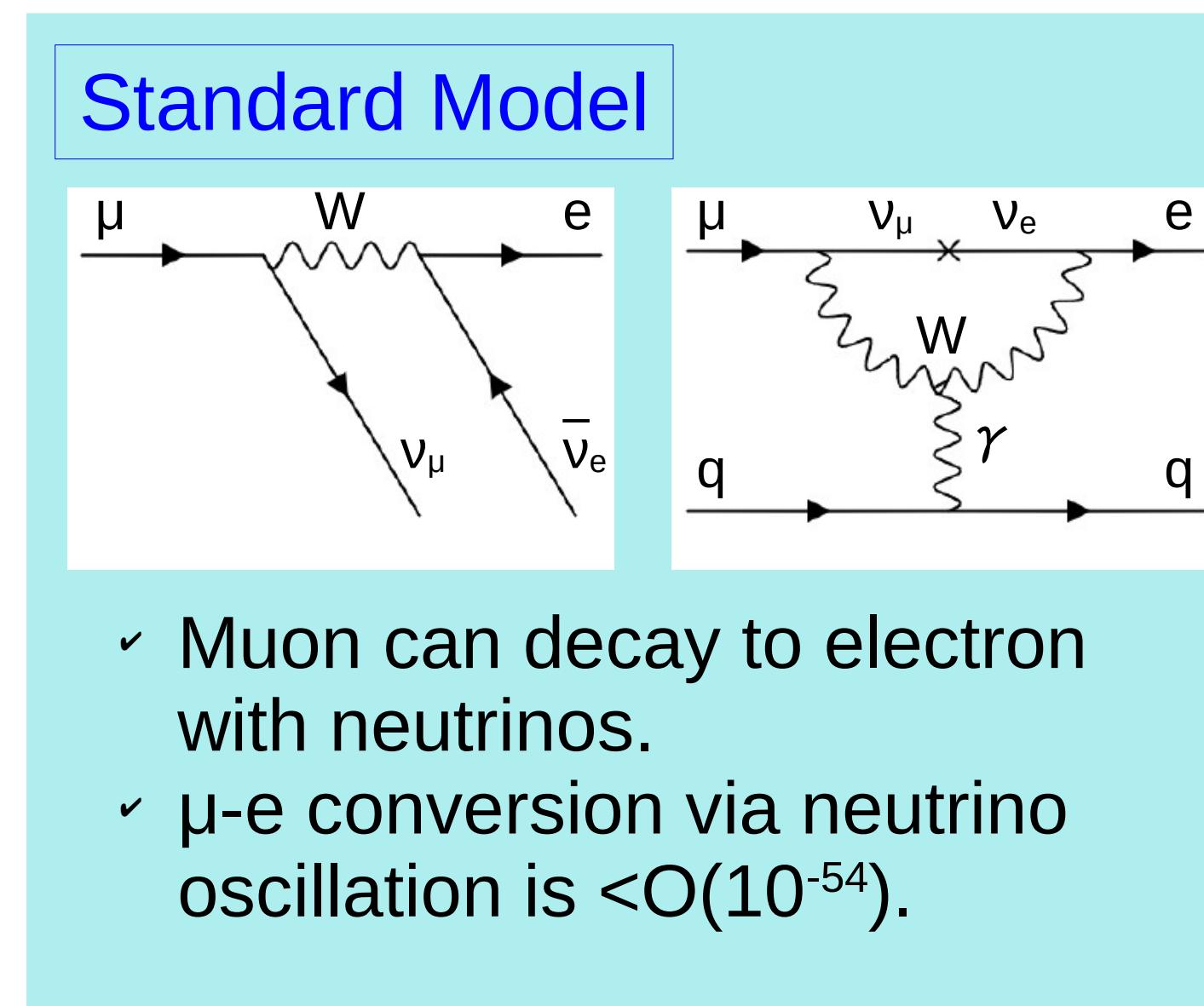
- COMET (COherent Muon to Electron Transition) starts from 2027 (one of the KEK core projects).
- They require rad-hard beam monitors for high-intensity 8 GeV protons / secondary particles.



What do we do in COMET: Muon to Electron Transition



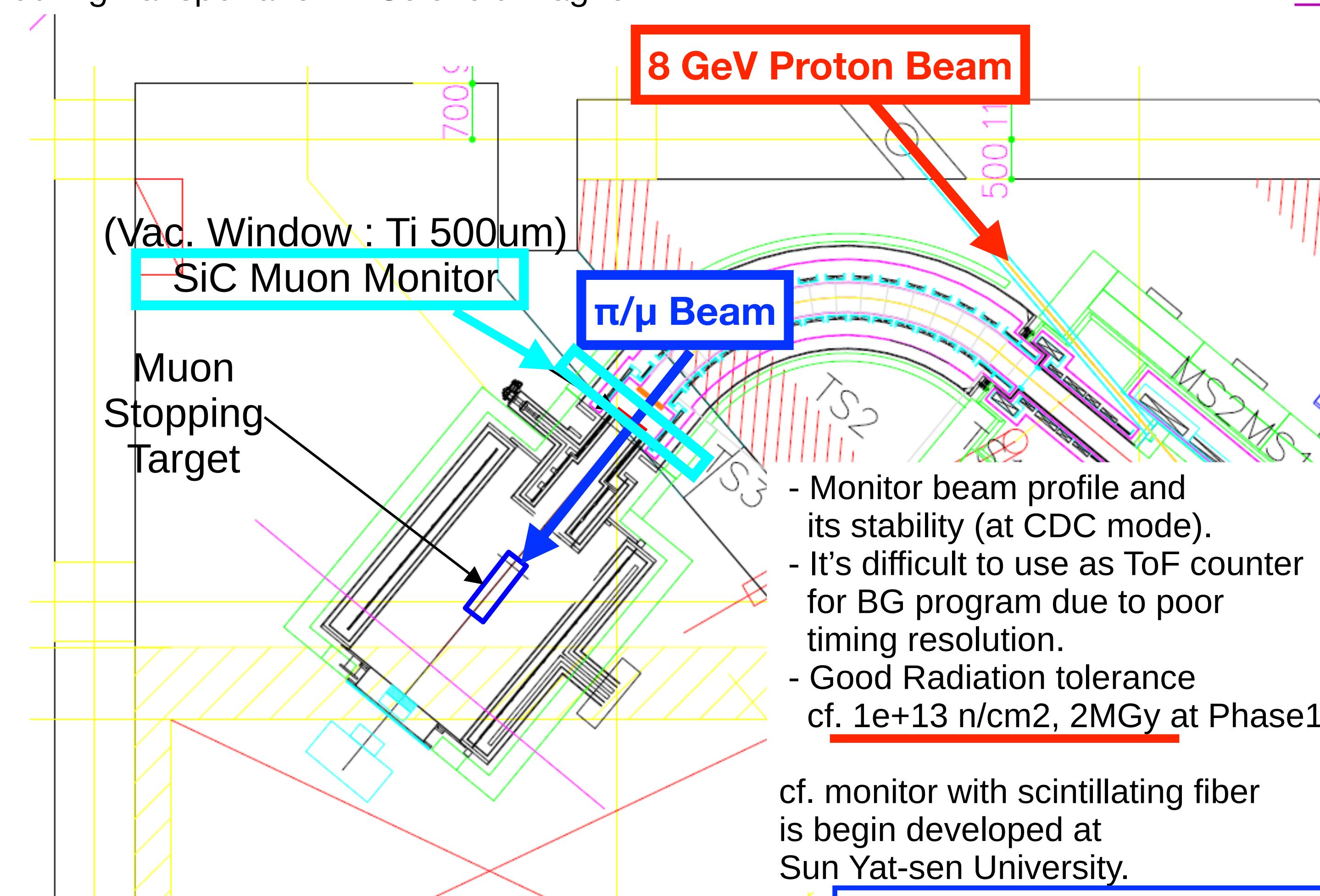
- Conversion of a muon to an electron is “**Charged Lepton Flavor Violation**” process and strongly prohibited in the Standard Model.
- Its discovery is an evidence of the new physics.



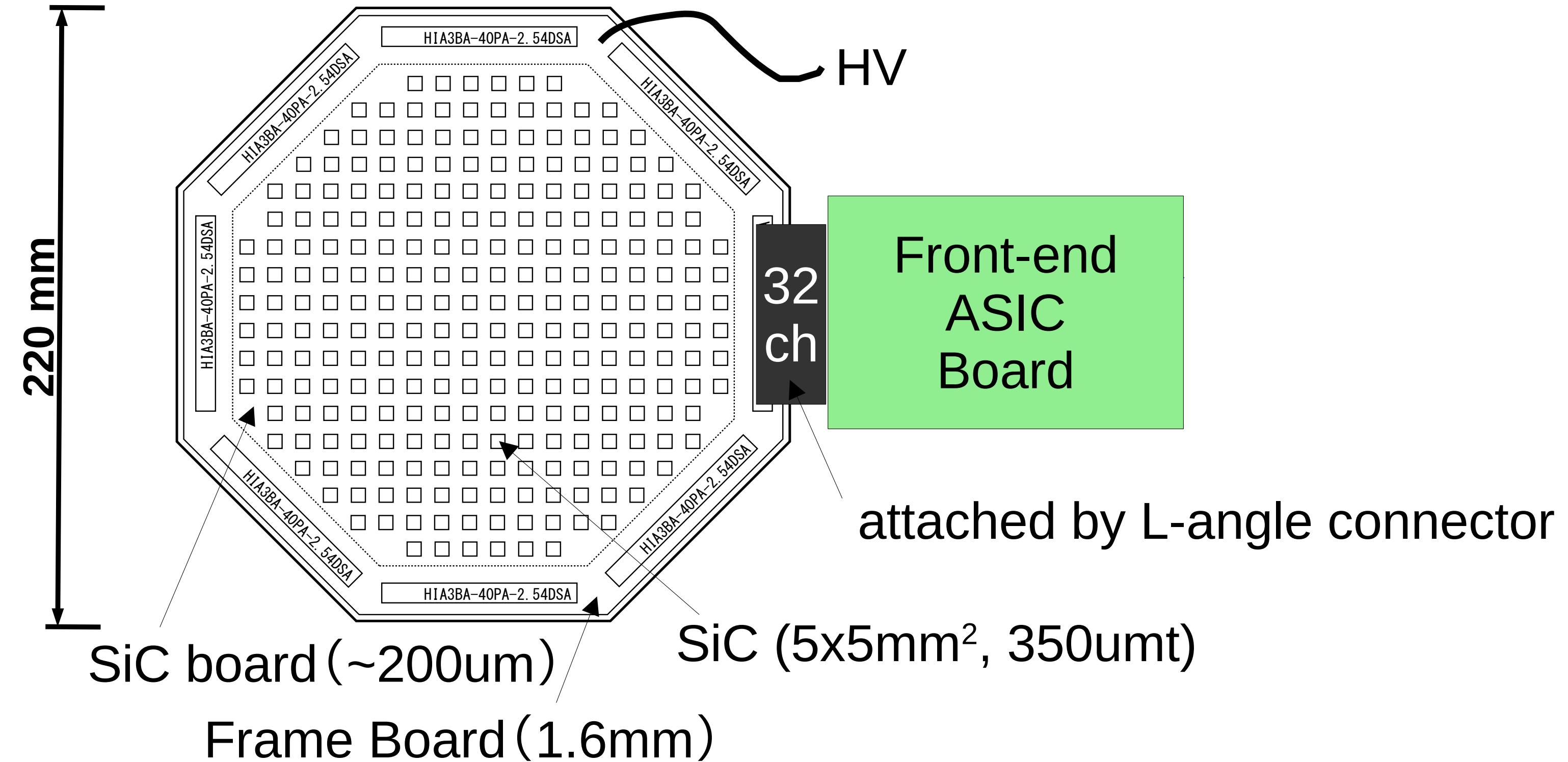
It's good opportunity to install “own” detectors to contribute to new physics!

COMET Phase-1

- 8 GeV proton beam is injected to Pion production target.
- Pions decay to muons during transportation in Solenoid magnet.

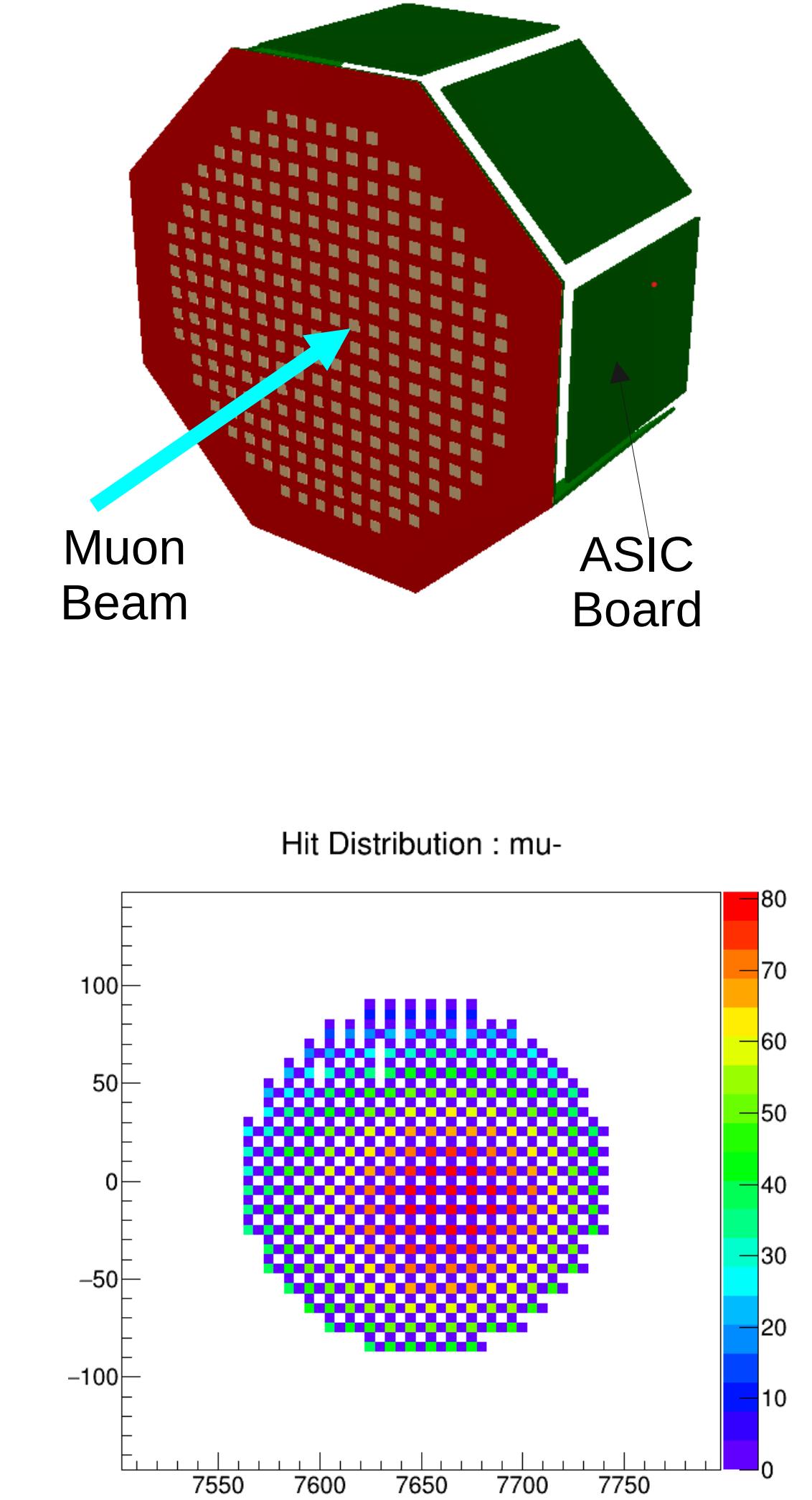


Concept of SiC Muon Beam Monitor



- Center region is thin Kapton board. Edge region is normal board to support the center region.
- Signal wires run between SiC sensors.

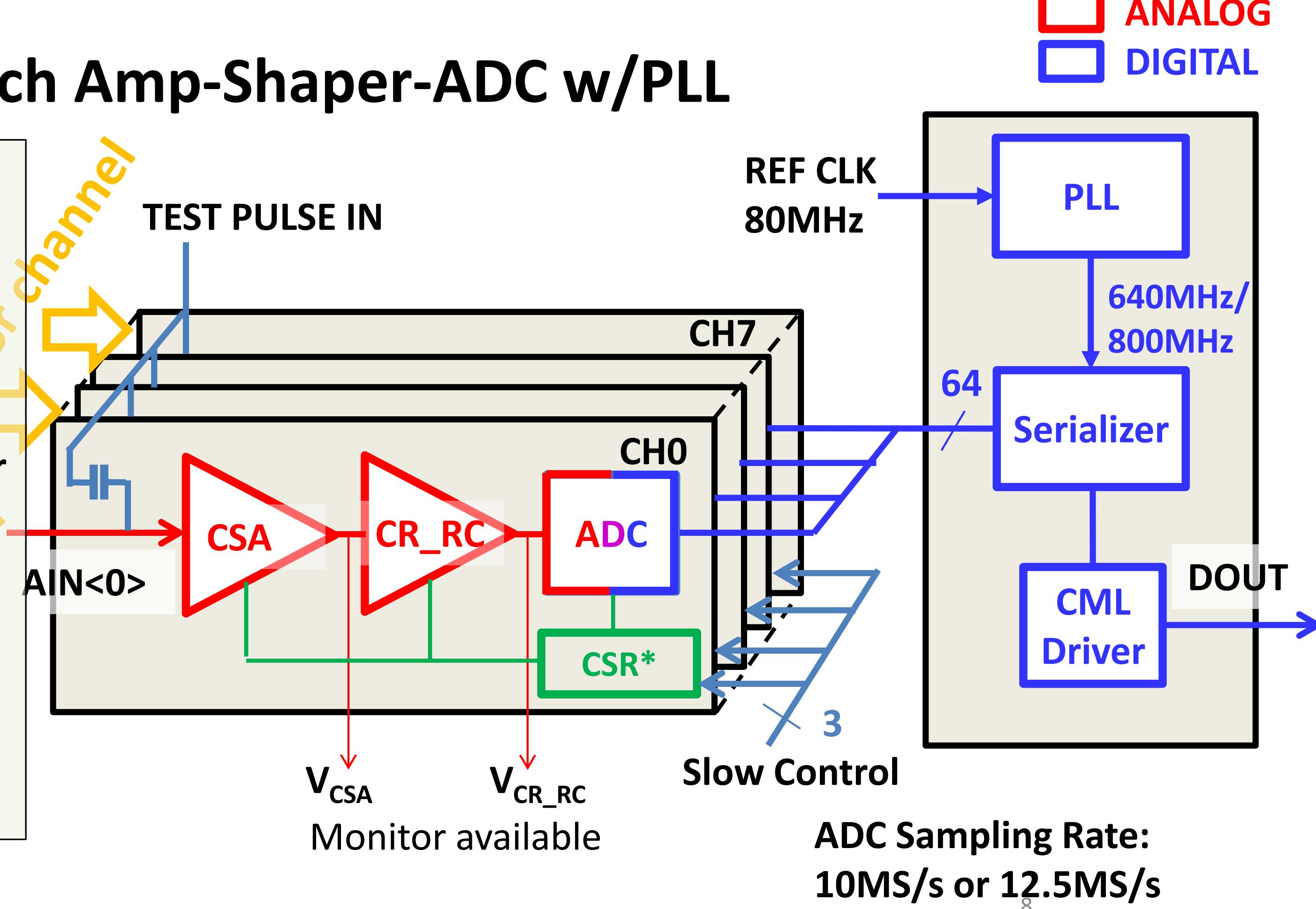
Q_{sig} : 75 MIPs (11 ke-/MIP), continuous waveform digitizing in 10 MHz.



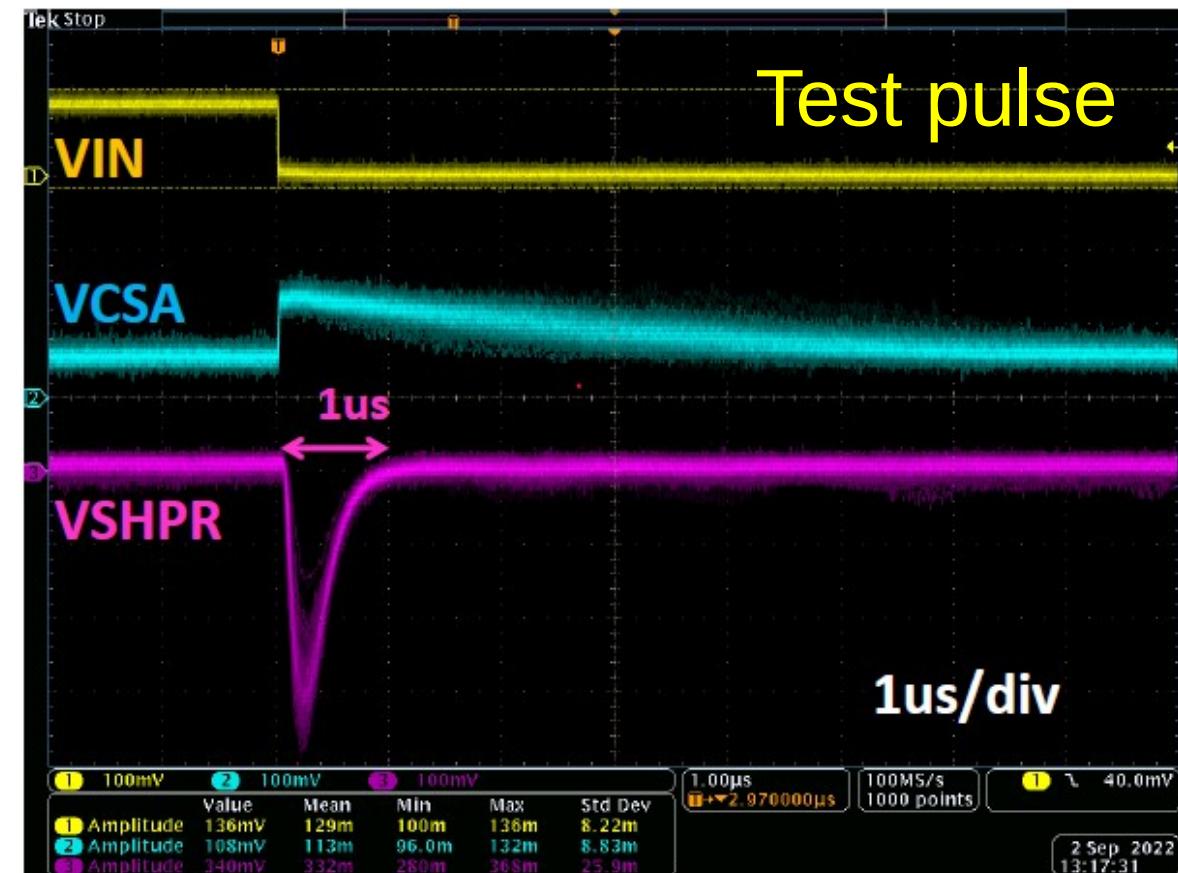
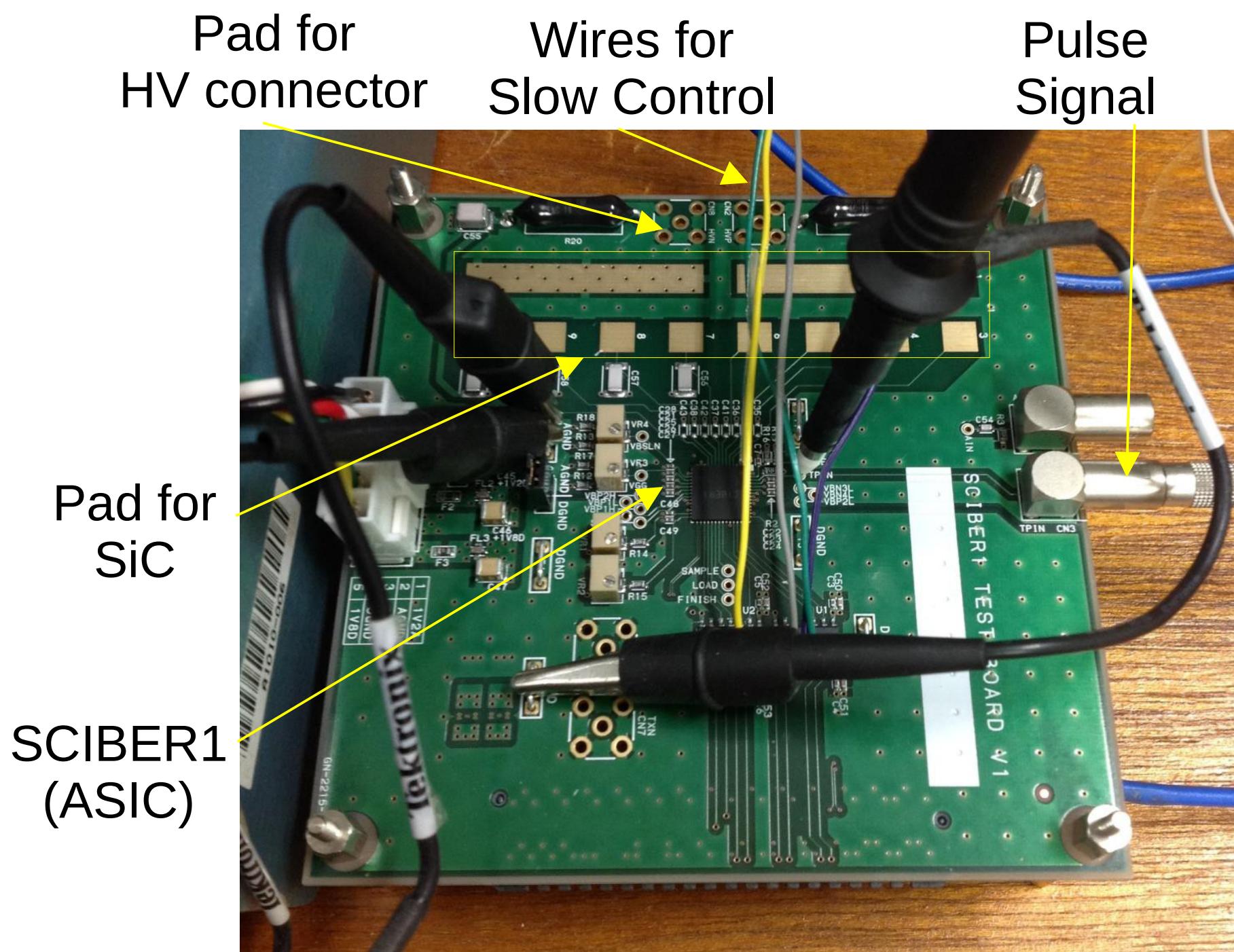
Readout electronics (SCIBER-1, Silicon Carbide IC for beam monitor)

- 8ch Amp-Shaper-ADC w/PLL

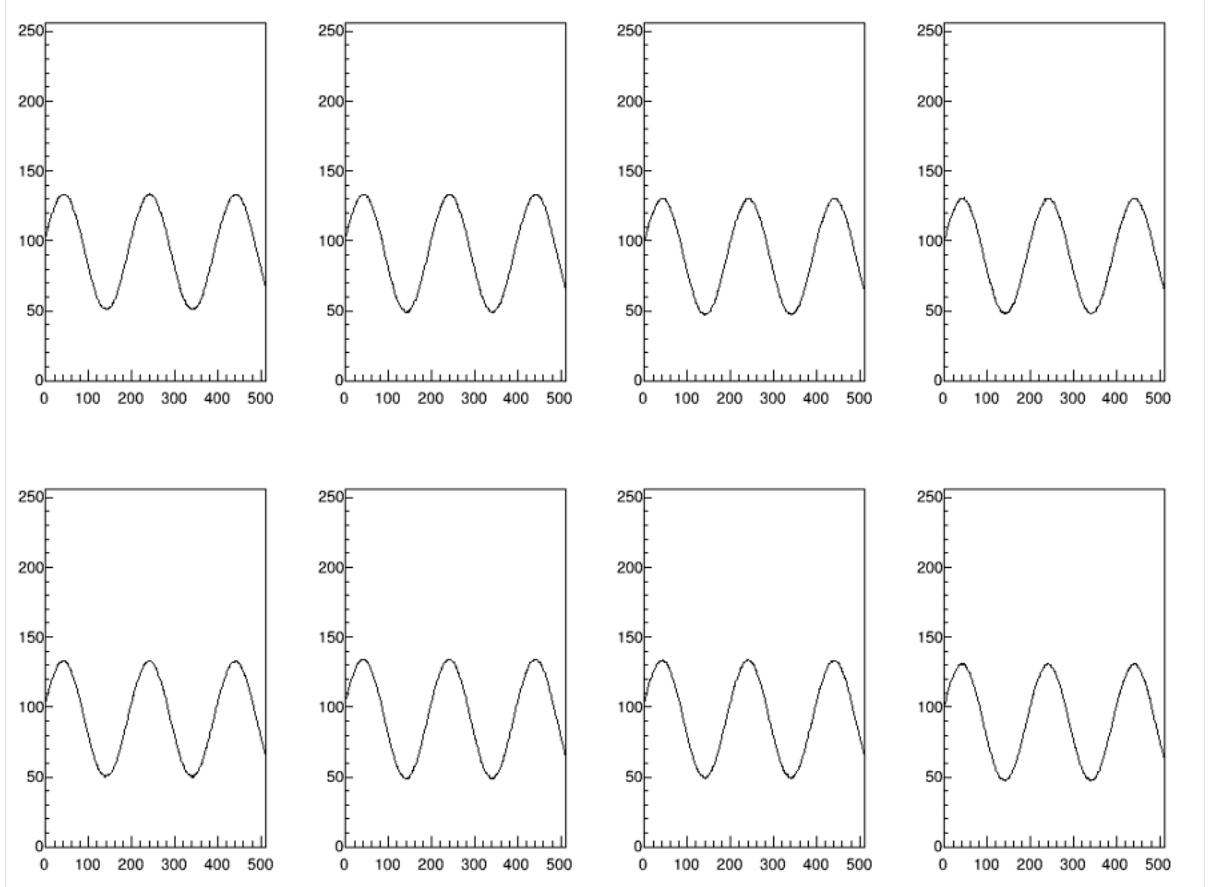
- Jakub's talk →
- Technology: TSMC CMOS 65nm LP
 - Supply Power: 1.2V (Core), 1.8V (I/O)
 - Chip size: 960um x 2,000 um
 - 8-bit SAR ADC
 - Sampling Rate: **12.5MS/s or 10MS/s**
 - PLL: 800MHz or 640MHz (w/80MHz REF CLK)
 - Inputs: 8 channels to connect sensors
 - Outputs: Digitized differential signals, CML



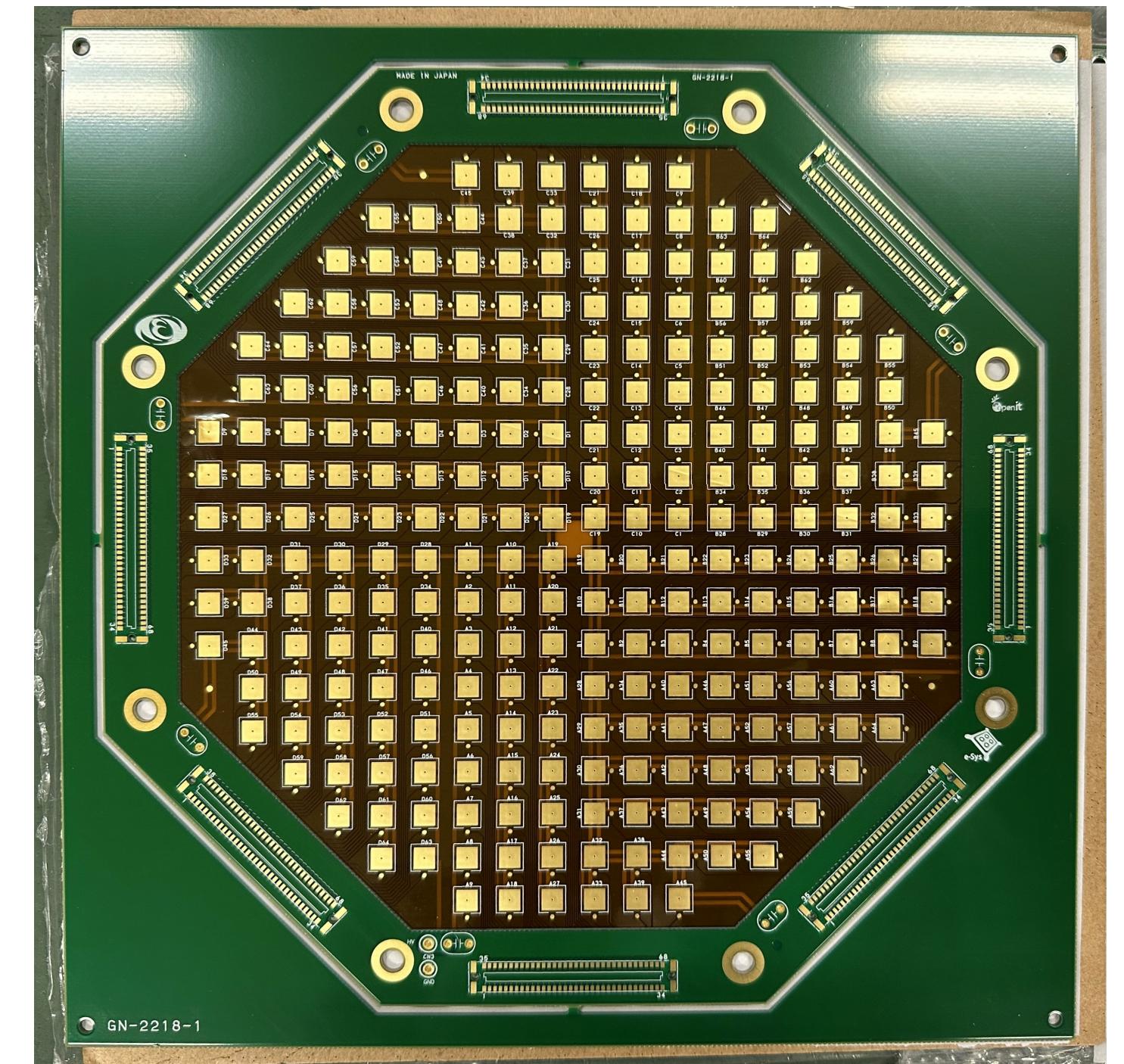
Preliminary test results



ADC outputs from 50 kHz sin-wave



Prototype of the SiC matrix board

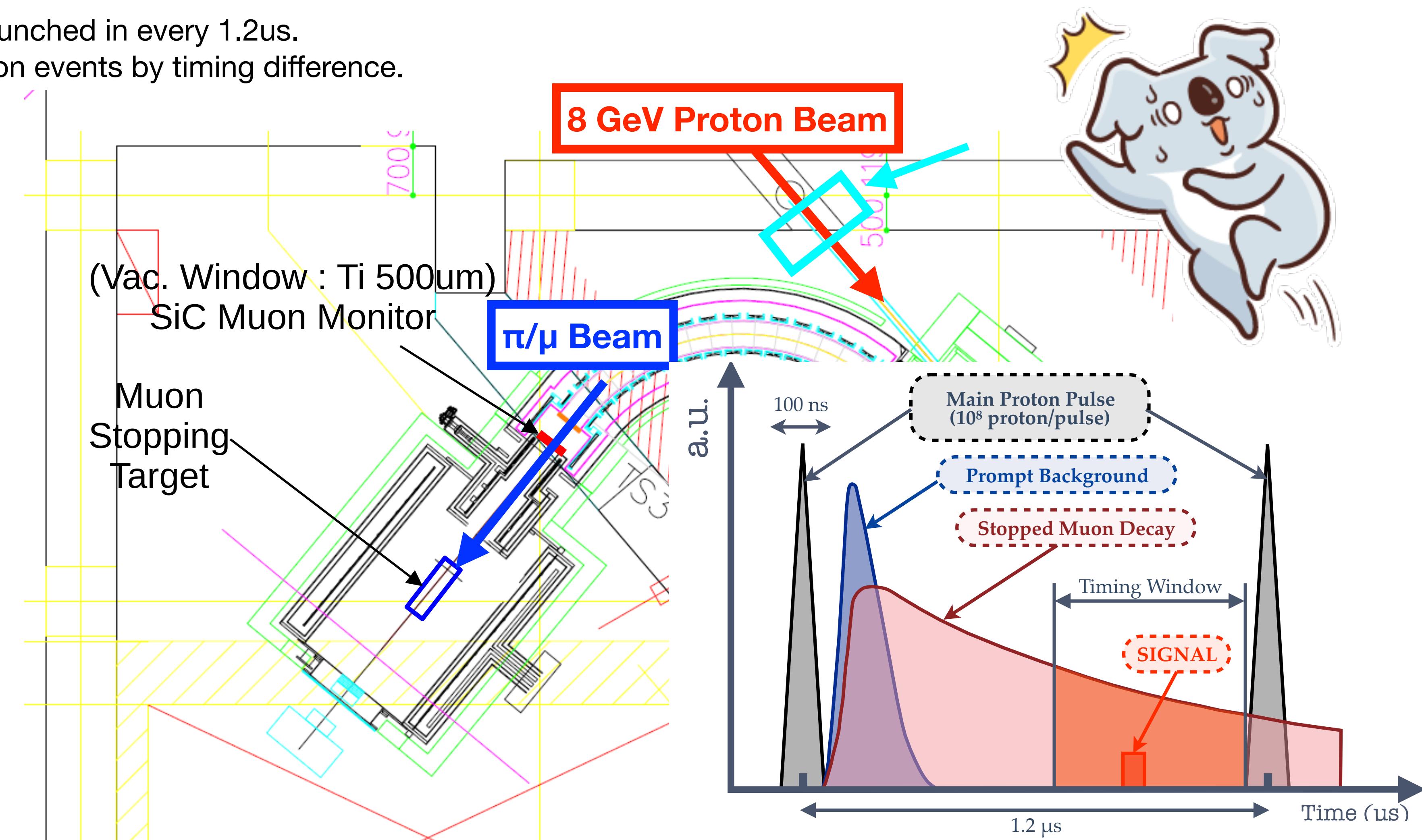


We can make the muon beam monitor on time before the COMET Phase-1.

*Commercial SiC epi-wafer is another option. (6k euros/wafer).

Further Needs for SiC sensors (more challenging)

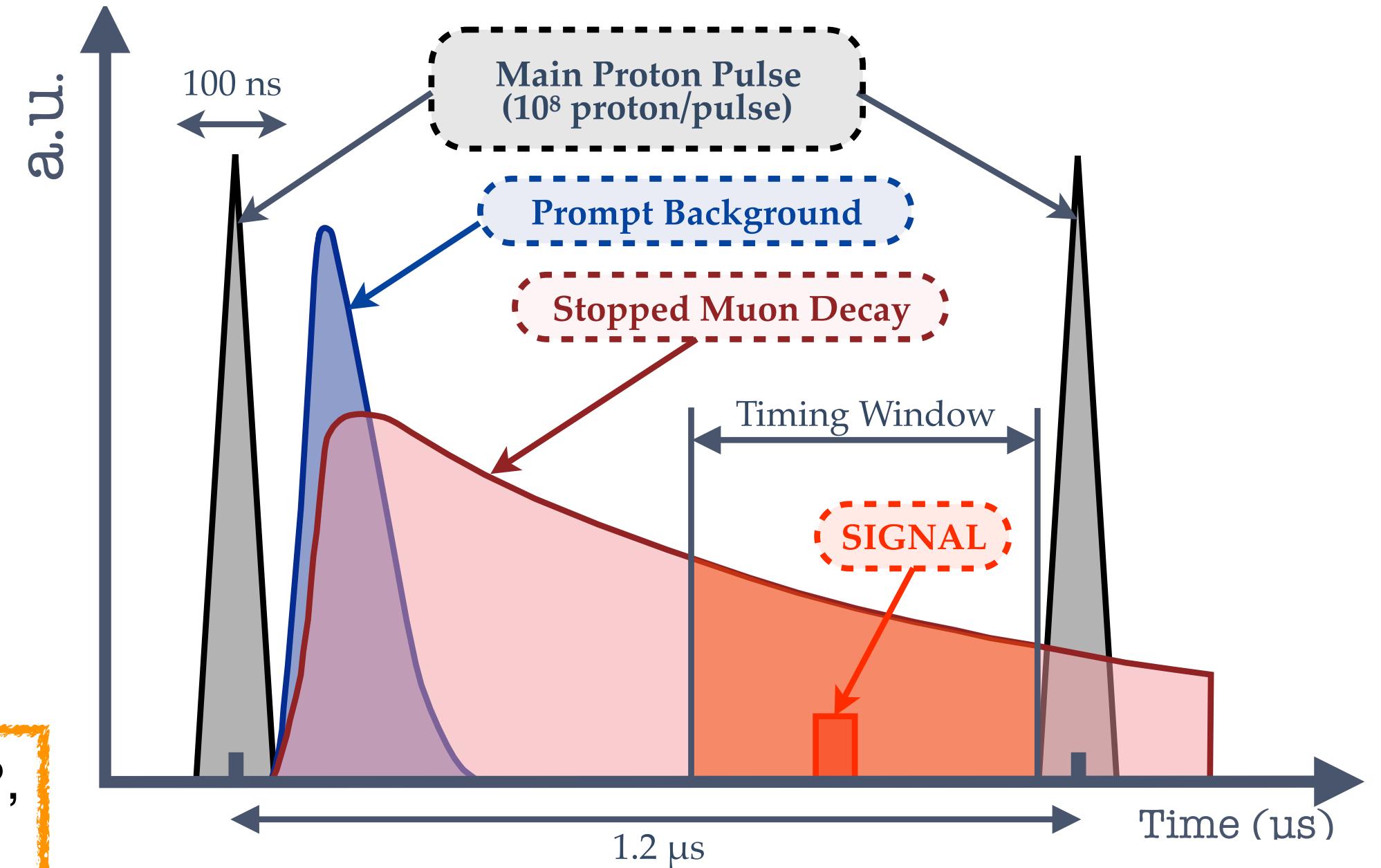
- 8 GeV proton beam is bunched in every 1.2us.
- Pion is BGD. Select muon events by timing difference.



Want to confirm no leaky protons (extinction) between bunches. → On-axis beam monitor with SiC!

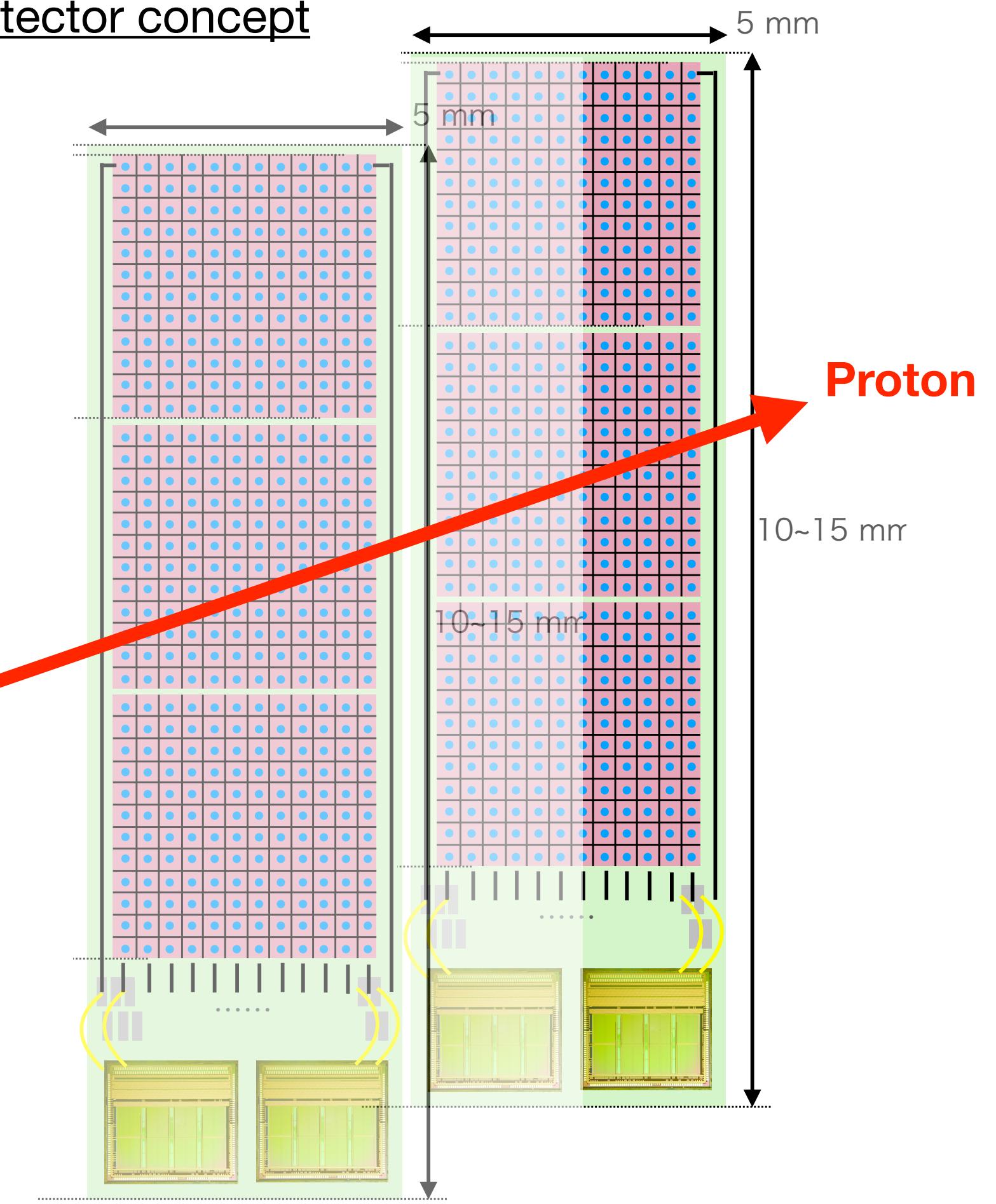
Requirements for Extinction Monitor

- Want to detect 1 proton after the main bunch
- Max. 1.6×10^7 proton/bunch with beam spot of $\phi \sim 1$ cm (TBD)
- Neutron fluence of 2.1×10^{14} n_{eq}/cm² during Phase-1



1. Relatively **large-area devices** can be fabricated in **wafer process**. → many detectors
2. Machine maintenance period is available every week. → We replace the detector!
 - **Electrodes should be segmented (pixel/strips) to reduce the event rates.**
 - Readout electronics placed sideways to avoid proton beam spot for radiation reason.

Detector concept

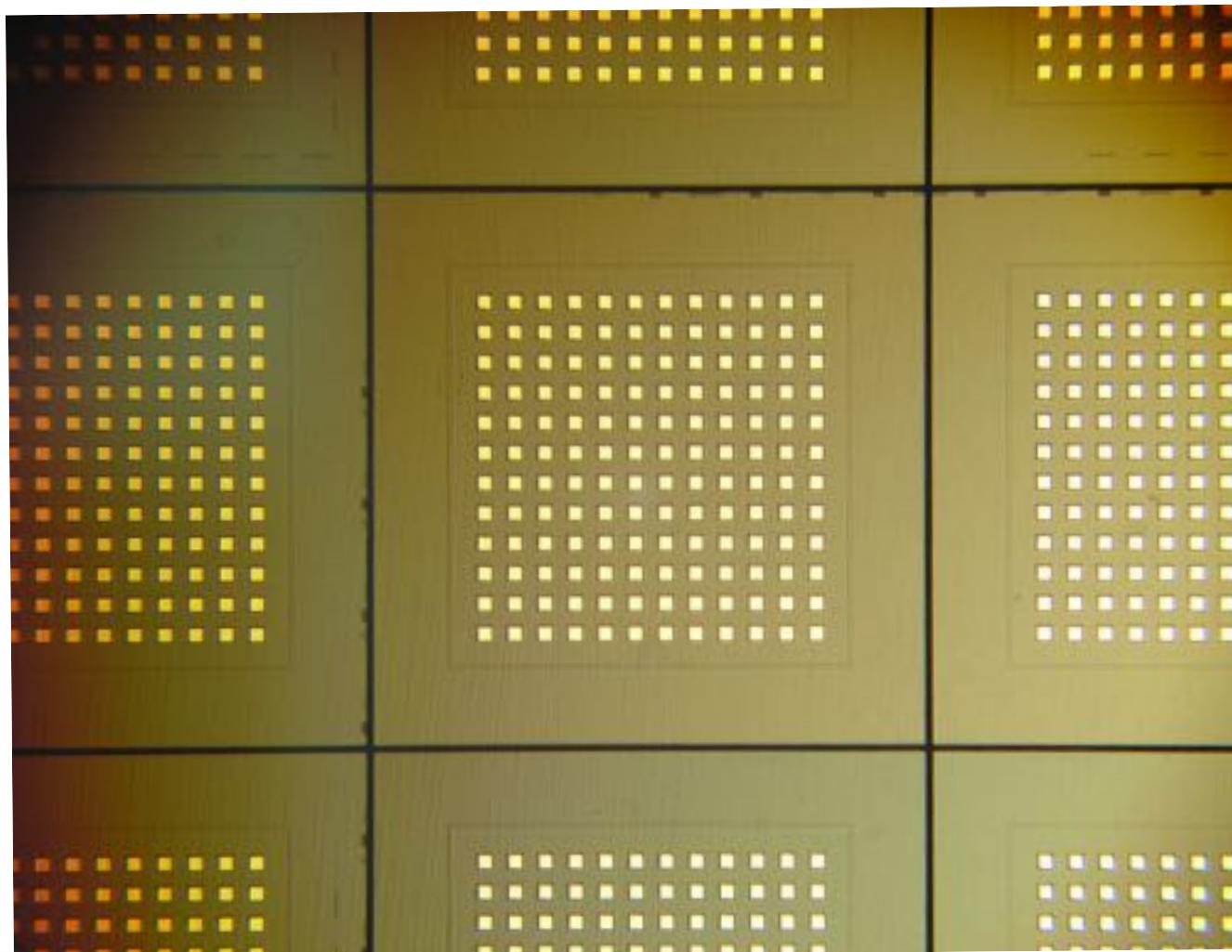


To prove the concept, we investigated the **sensor segmentation** and performance uniformity.

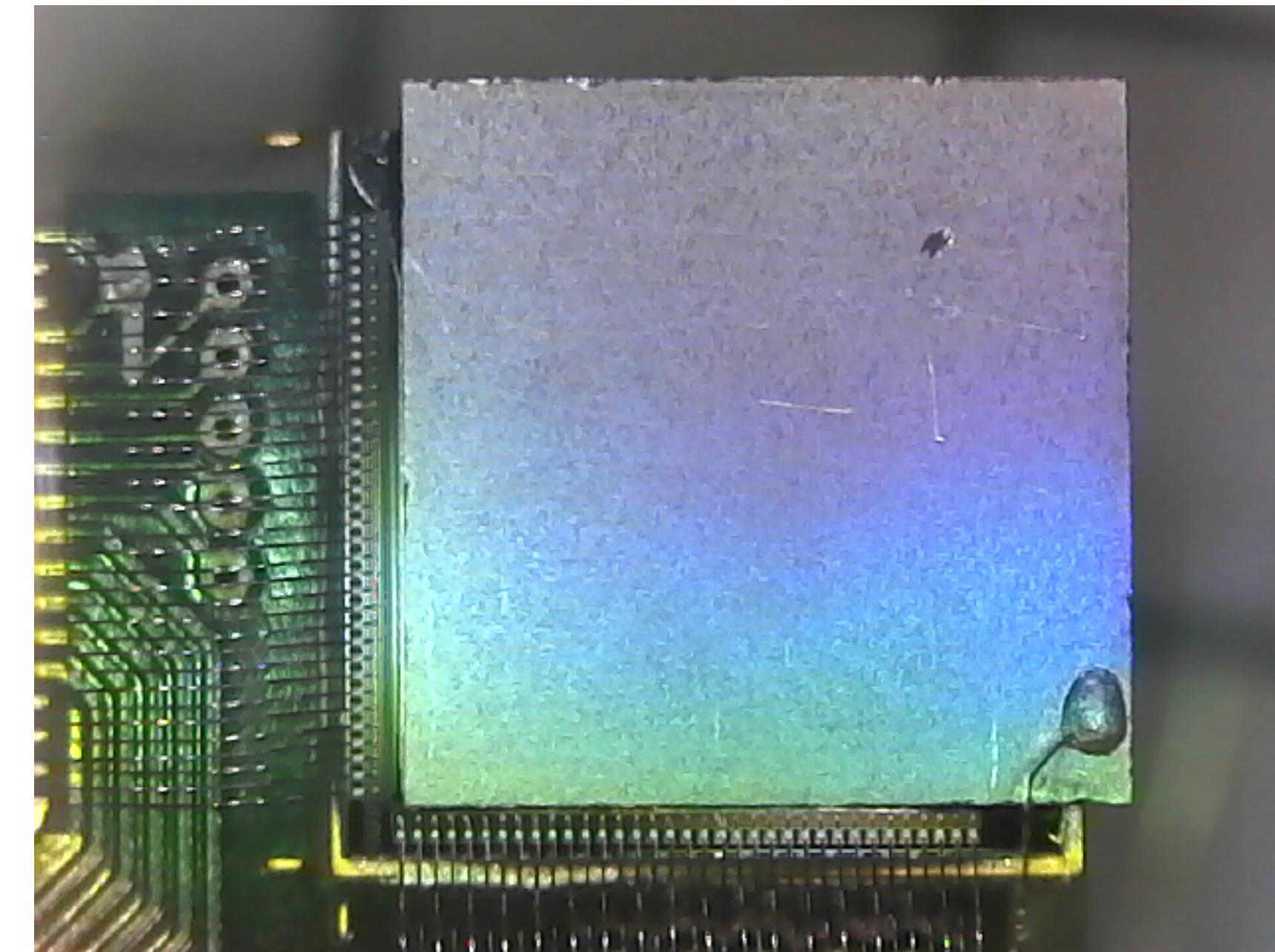
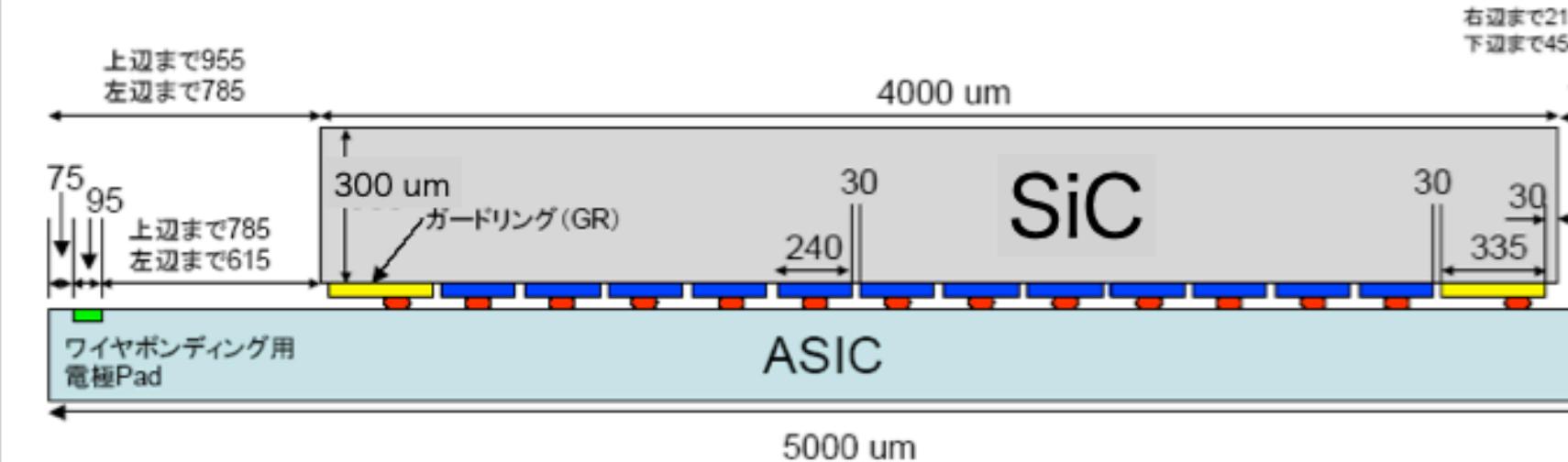
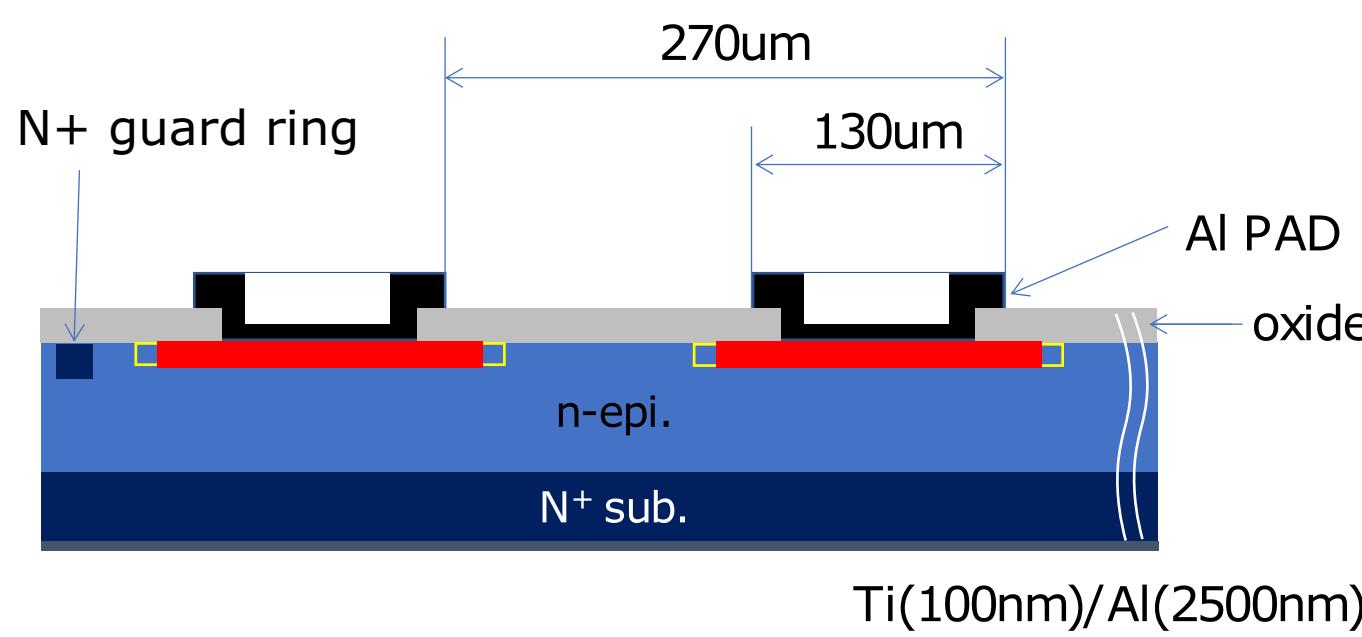
Sensor segmentation (hybrid pixel detector)

- 5 mm x 5 mm with 12 x 12 electrodes, 270 um pitch
- readout with low-noise ASIC
- Au/In stud bump technology

(a)



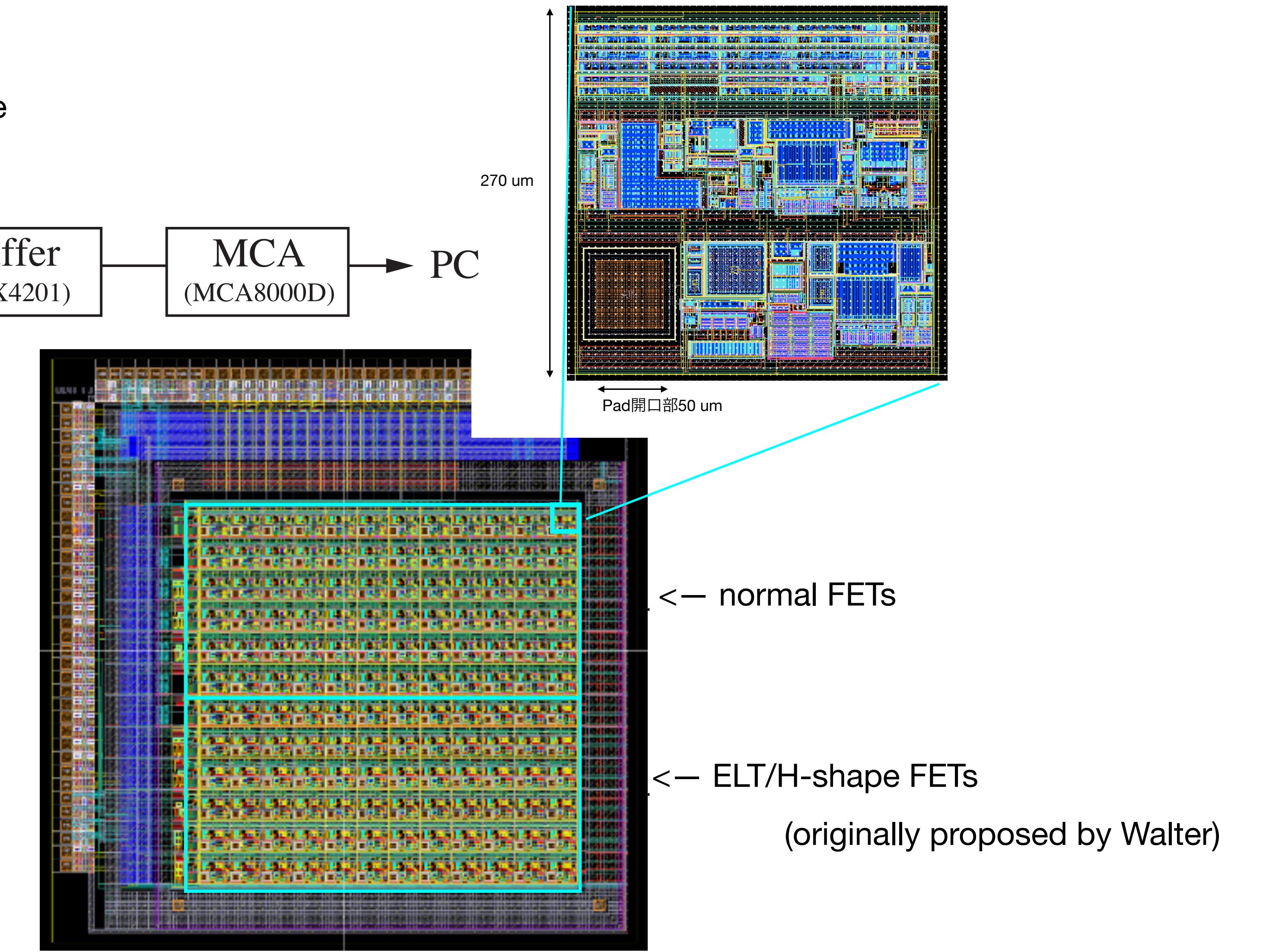
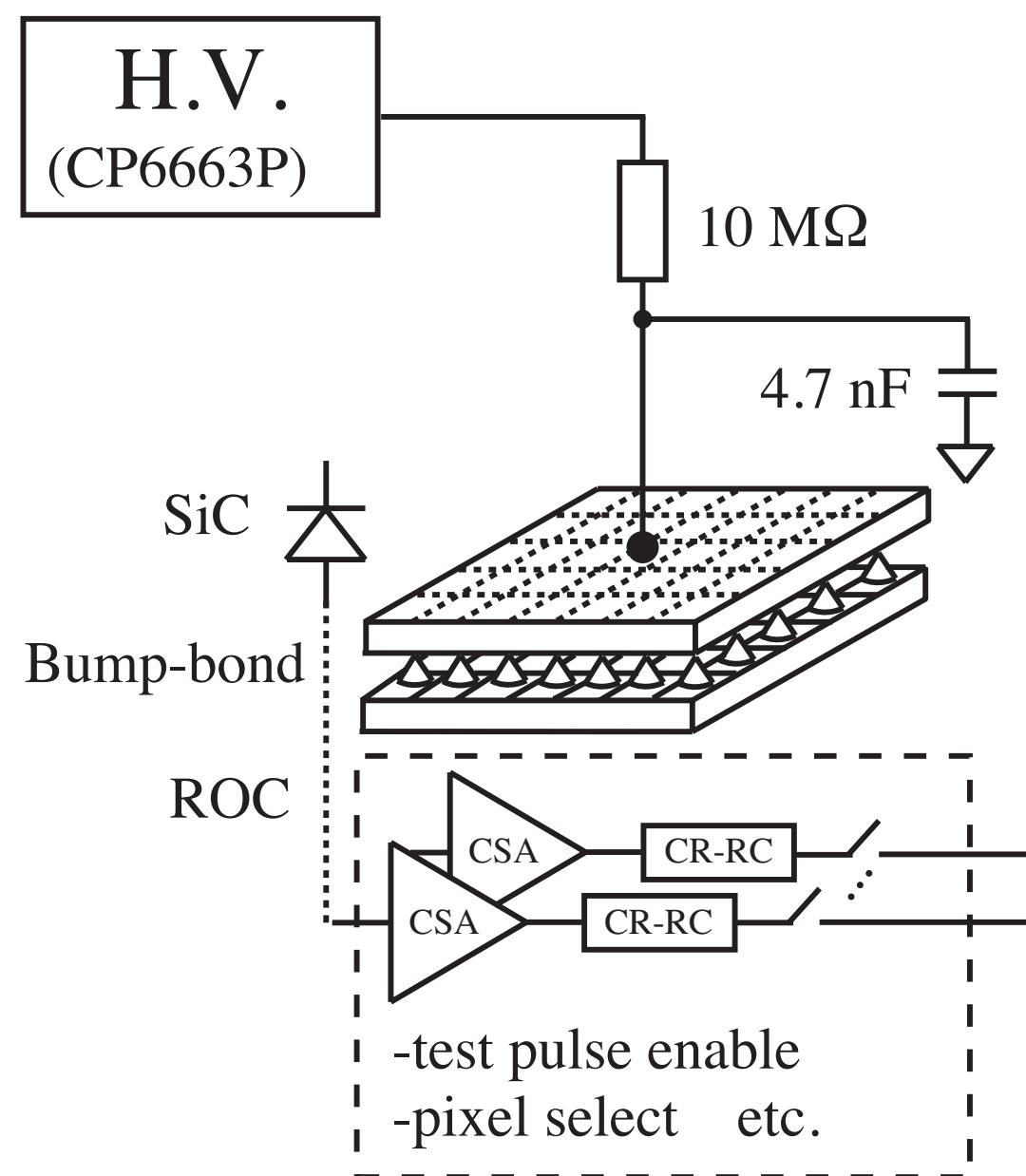
(b)



Passivation (Parylen or Silicone rubber) is necessary to prevent electric discharges @1 kV.

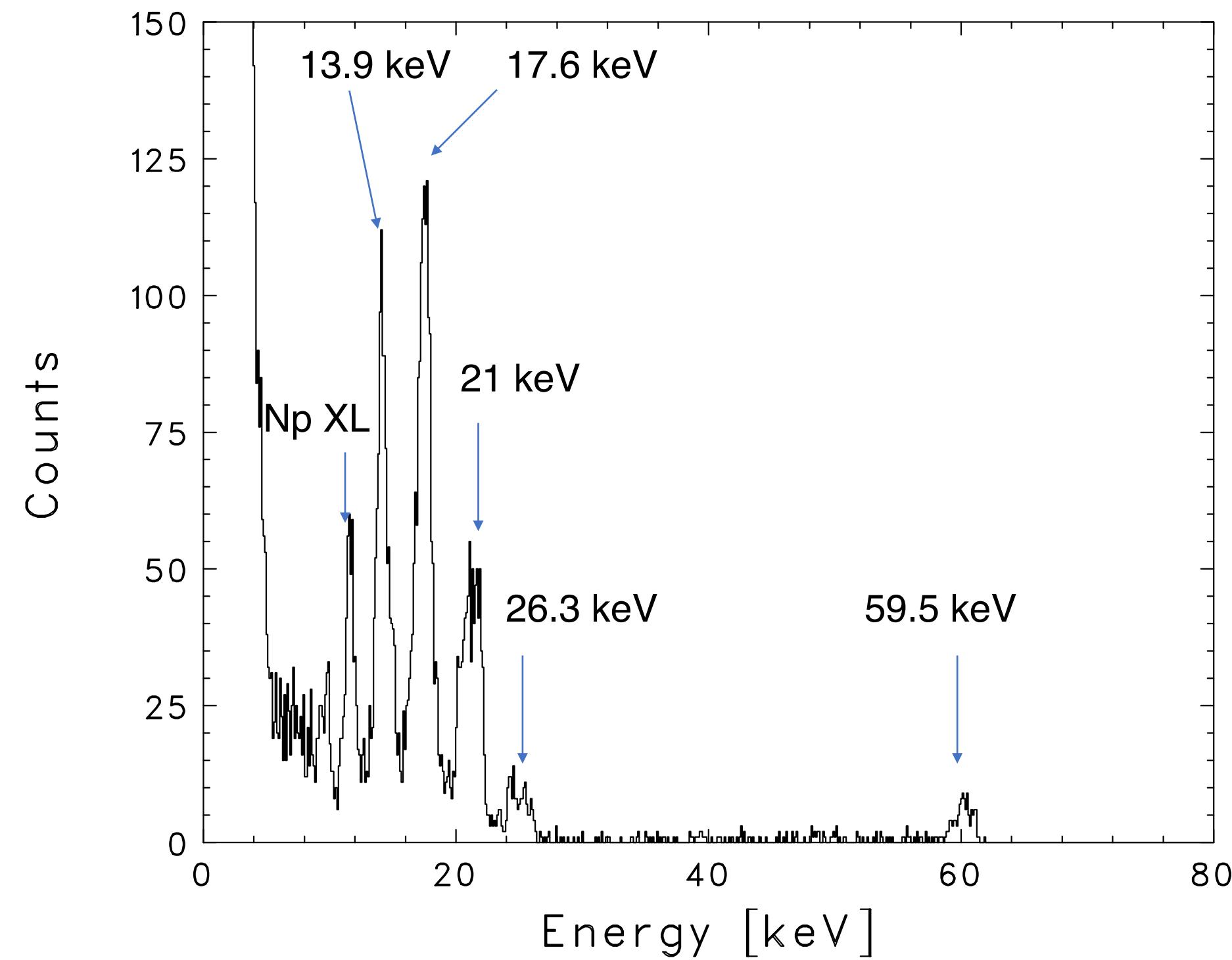
Readout ASIC

- TSMC 0.35 um CMOS
- 270 um x 270 um pixel size, 12 x 12 pixel cells
- CSA (DC-coupling to SiC)+Shaper with 5 us shaping time
- Used wirebonding for DC-power supply/control signals



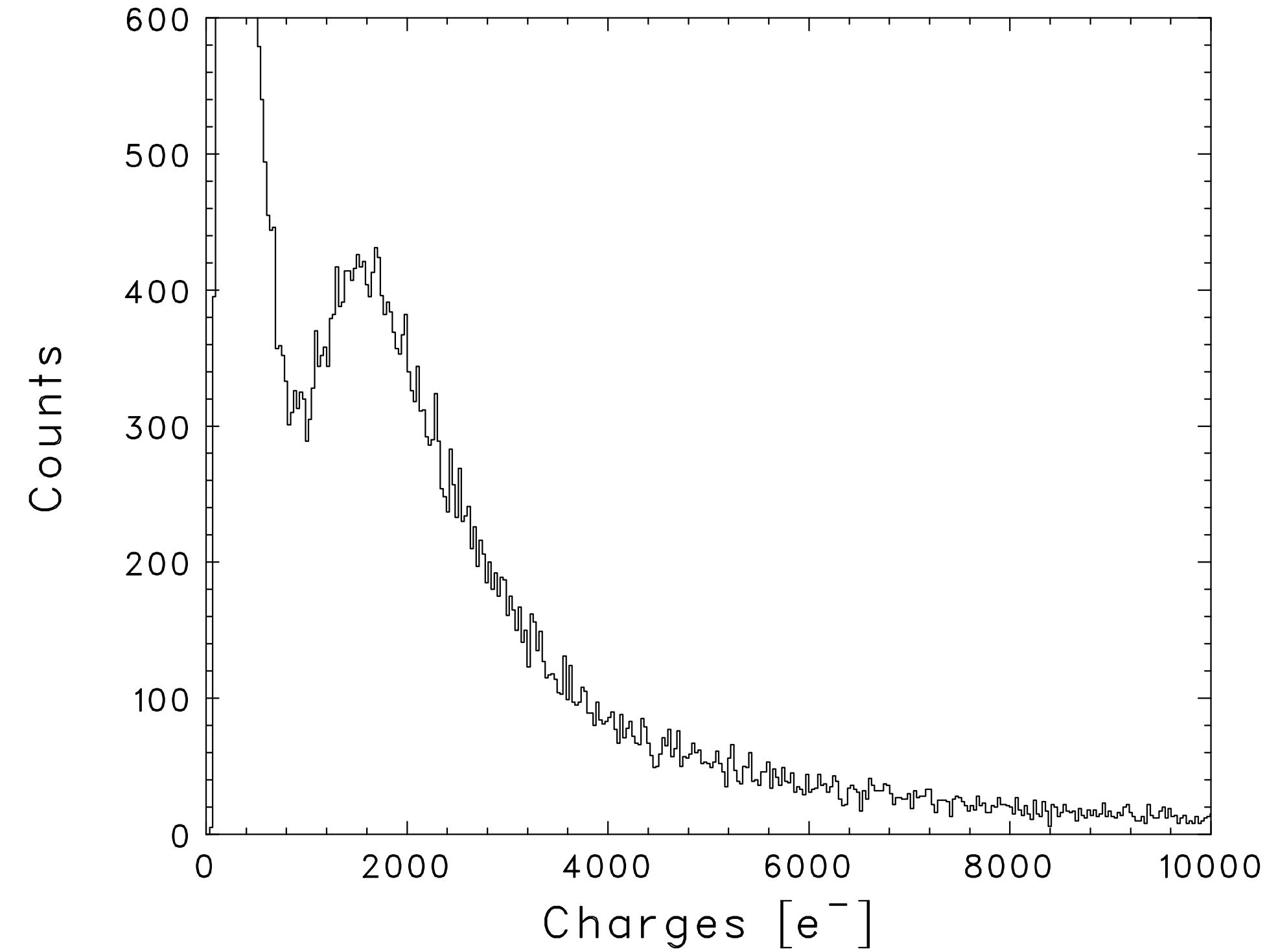
Spectral performance

- HV: +600 V
- Exposure: 3 days
- Mode: HG



FWHM: 1.72 keV @ 17.6 keV

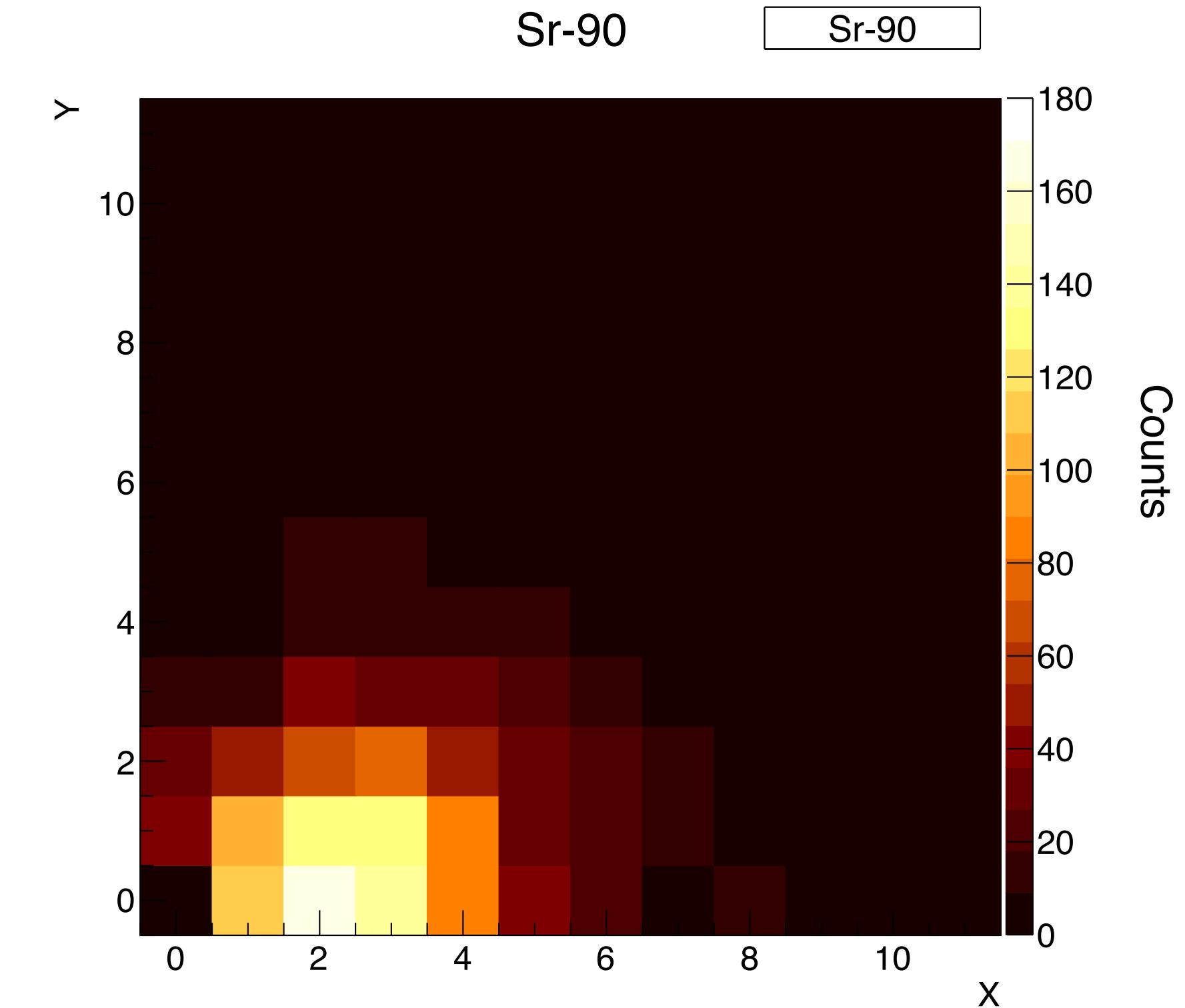
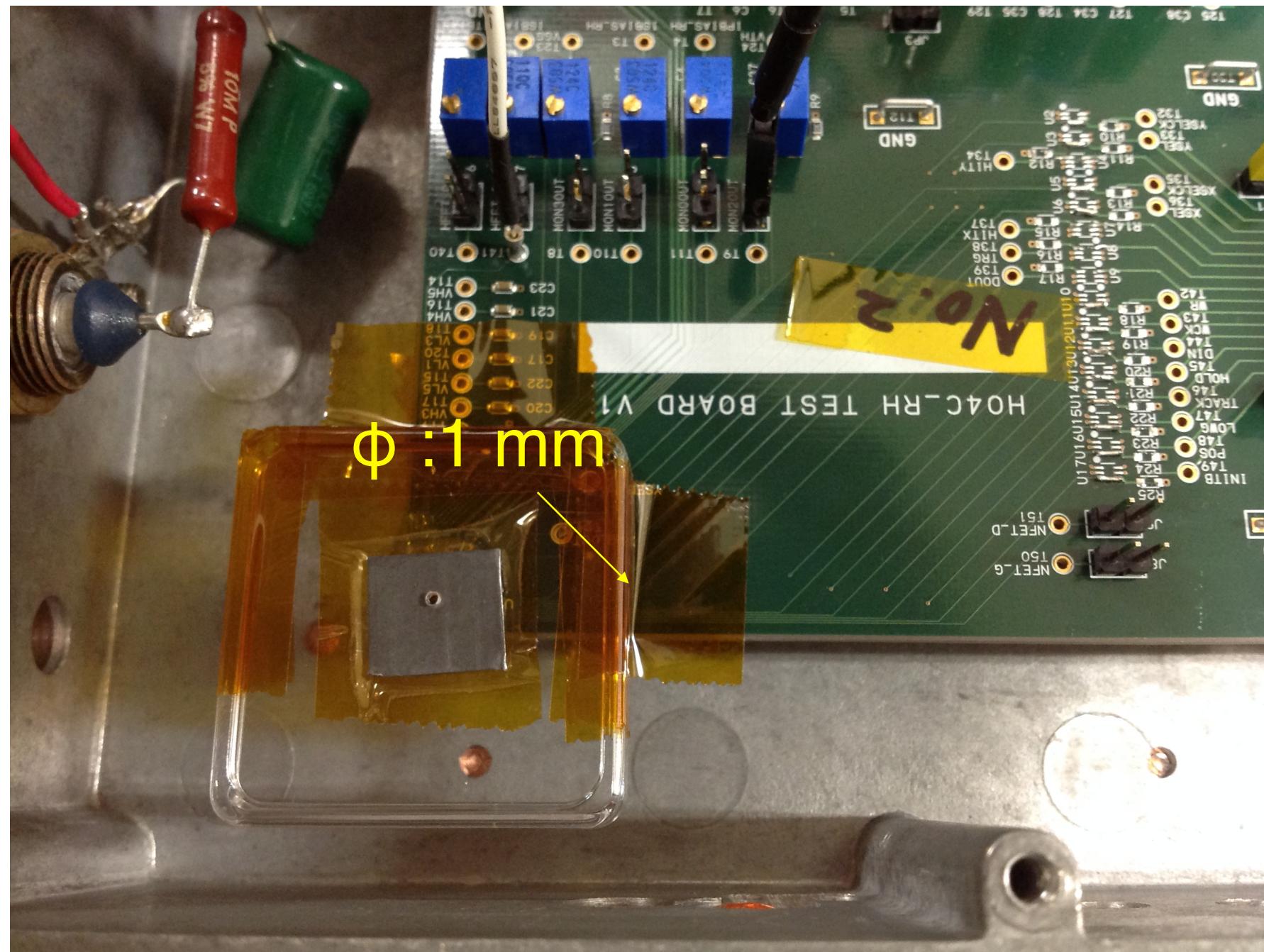
- HV: +600 V
- Exposure: 0.5 days
- Mode: HG



Confirmed β -ray events from all pixels.

Imaging performance

- Blind search of pinhole position in Pb sheet
- Count Sr-90 events between 1000-6000 e-, 1 min for each pixel



- Finer segmentation is realistic and nice uniformity expectable in larger devices
- SiC performance is closing to silicon.
- Still long way to reach the proton extinction monitor, but SiC is an important candidate.

Needs of Diamond sensors

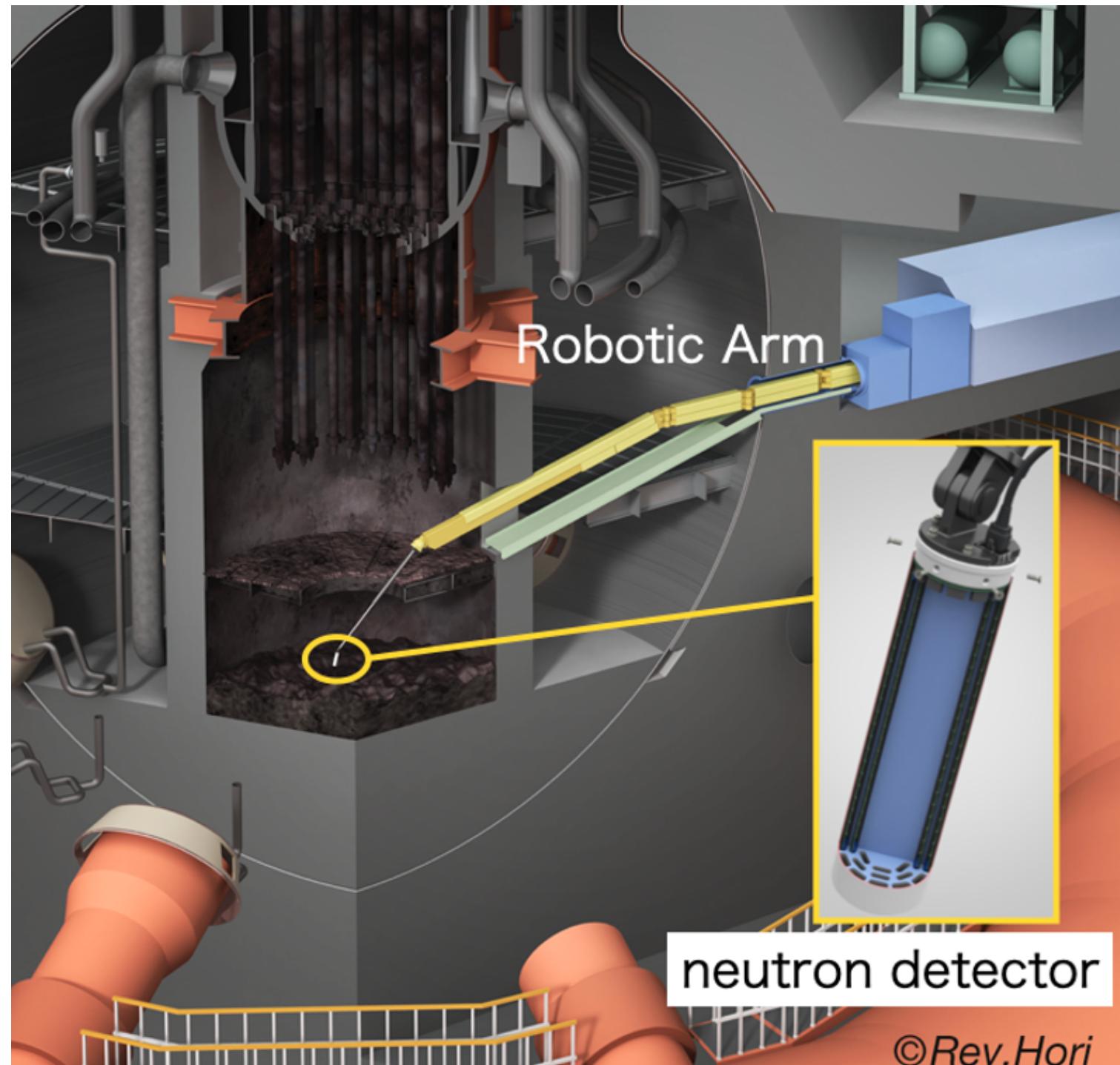
- Nuclear decommission is on-going at Fukushima Nuclear Power Plant.
- Need “eye” to know exact locations of nuclear debris for robotic arms (at least monitor the neutron flux to protect workers).
- No data of radiation environment yet.

Gamma-rays from Cs every direction: max. 1 kGy/h (100 krad/h)

Site of the Fukushima Nuclear Power Plant



Concept of the neutron detector



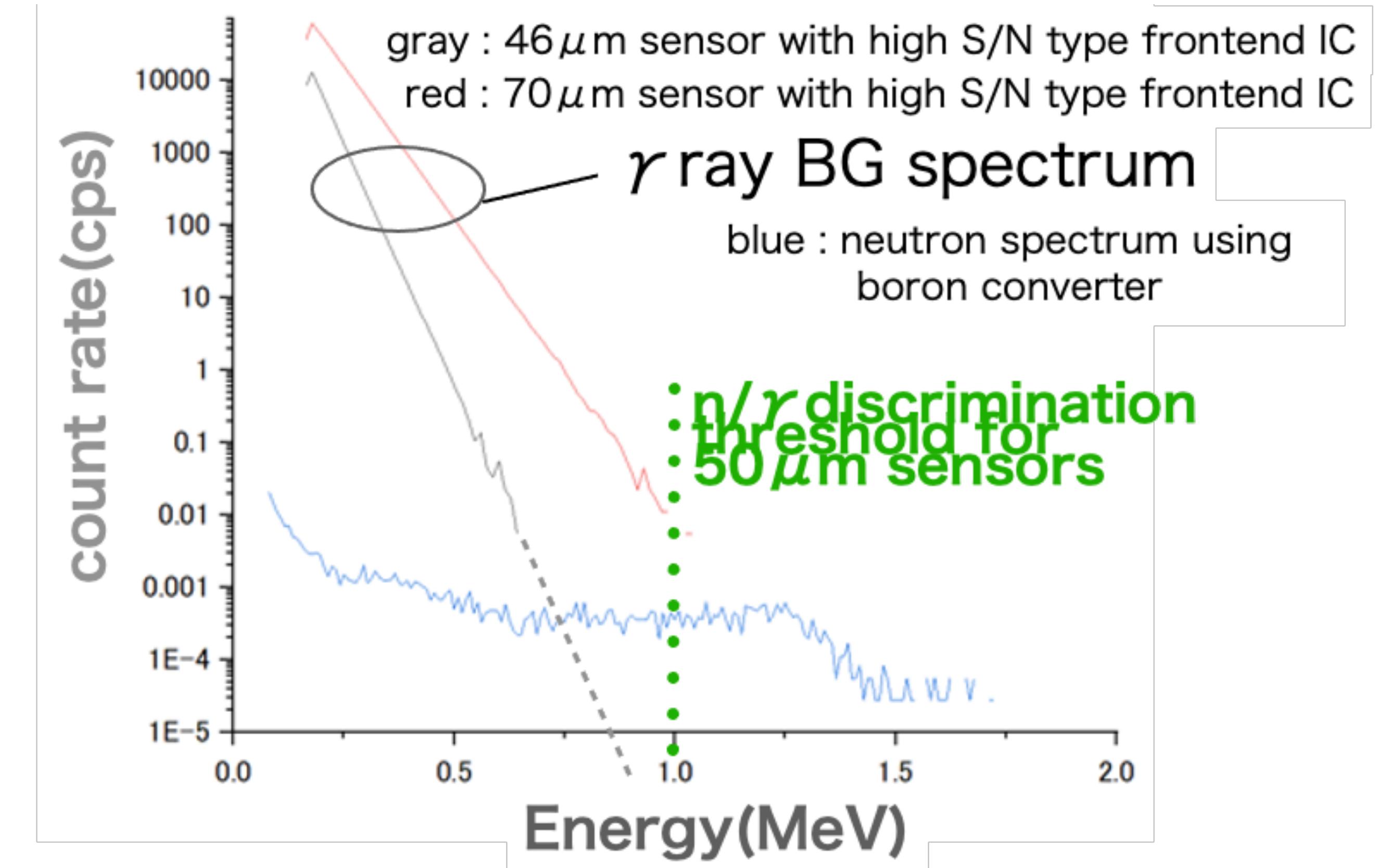
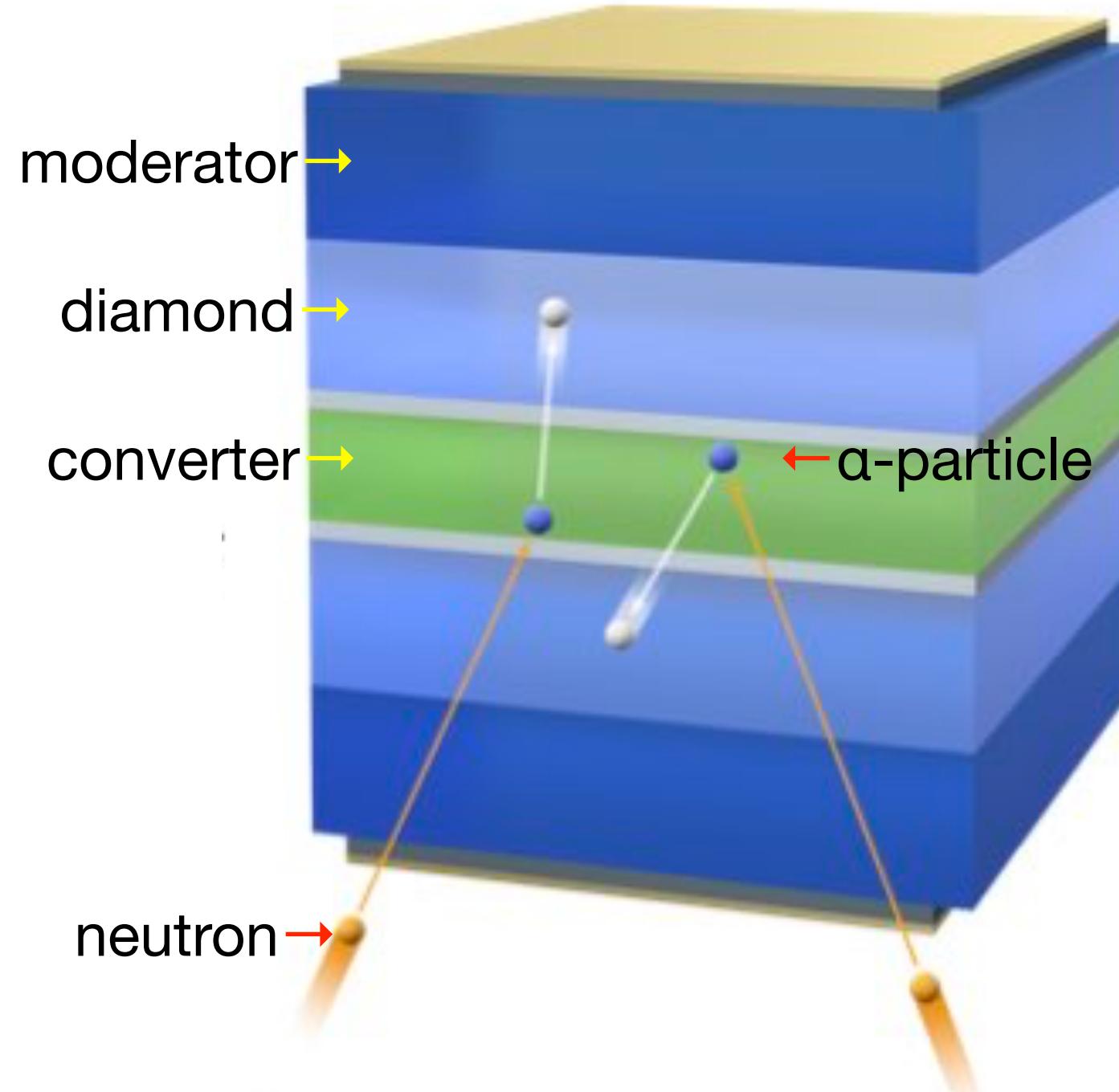
Pacific ocean

Under high γ -BGD, thin sensors are required for neutron detection. →Diamond!

Concept of neutron detector

- Use neutron converters (${}^6\text{LiF}/{}^{10}\text{B}_4\text{C}$) and detect alpha-particles
- Detect neutrons (~1 Hz) under high gamma-ray BGD (~1 MHz)
- Sandwich configuration to increase detection efficiency

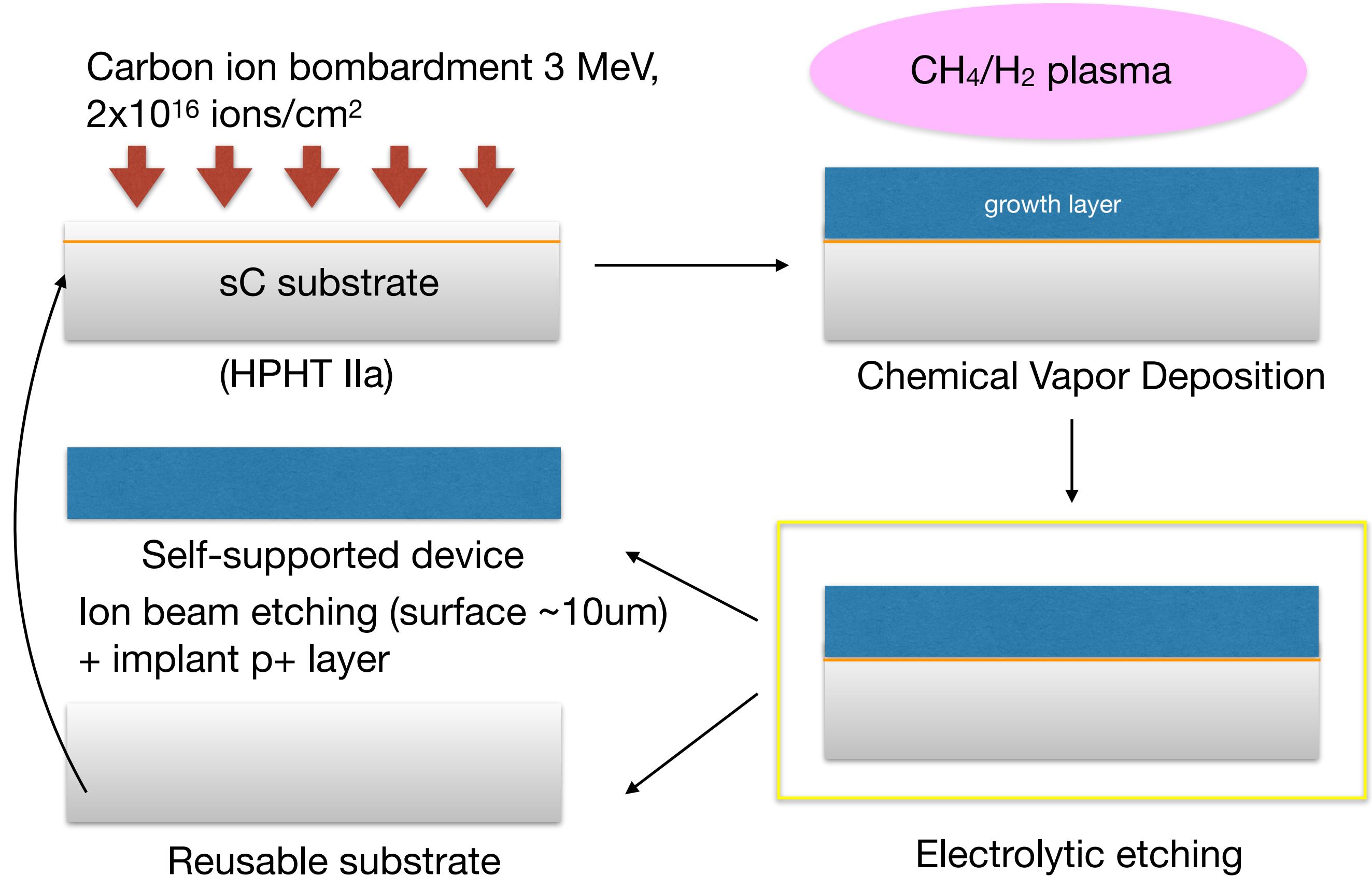
Concept of the neutron detector



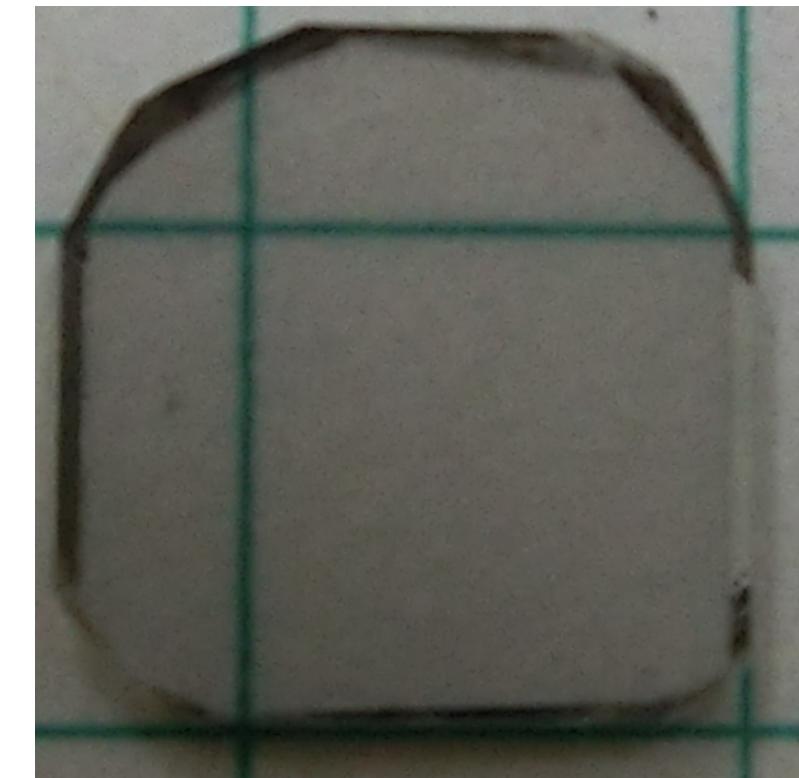
To detect neutrons with 1 Hz, we need more than 1000 diamonds! How to realize such number?

Device fabrication: self-supported diamond

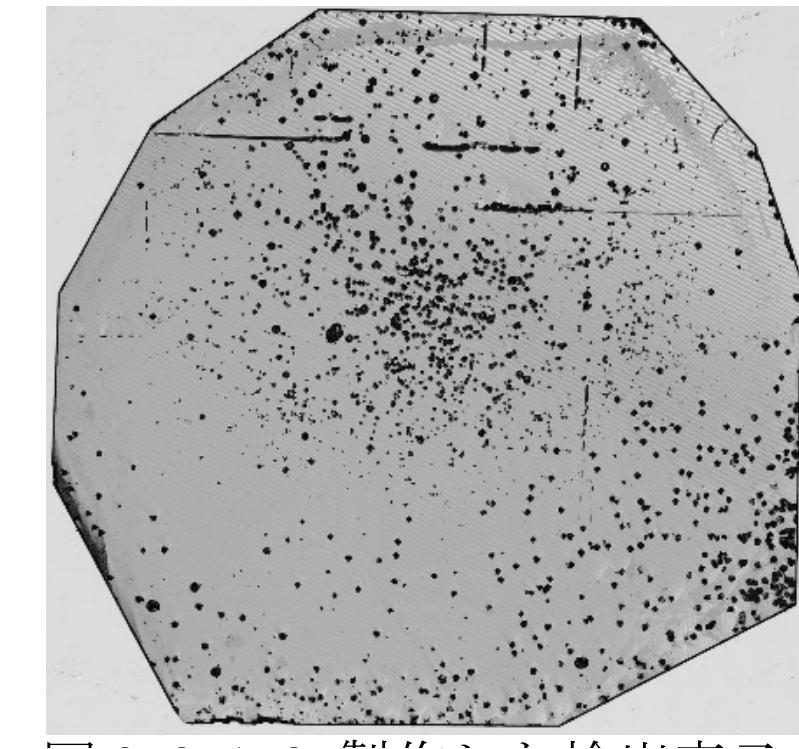
- Self-supported diamond with **reusable substrate**
- 30-50 um thickness to avoid cracking
- Na-Nd: 10^{11} - 10^{12} cm $^{-3}$
- Long process time (>2 weeks), yield issues, wire-boning etc.



Single-crystal substrate



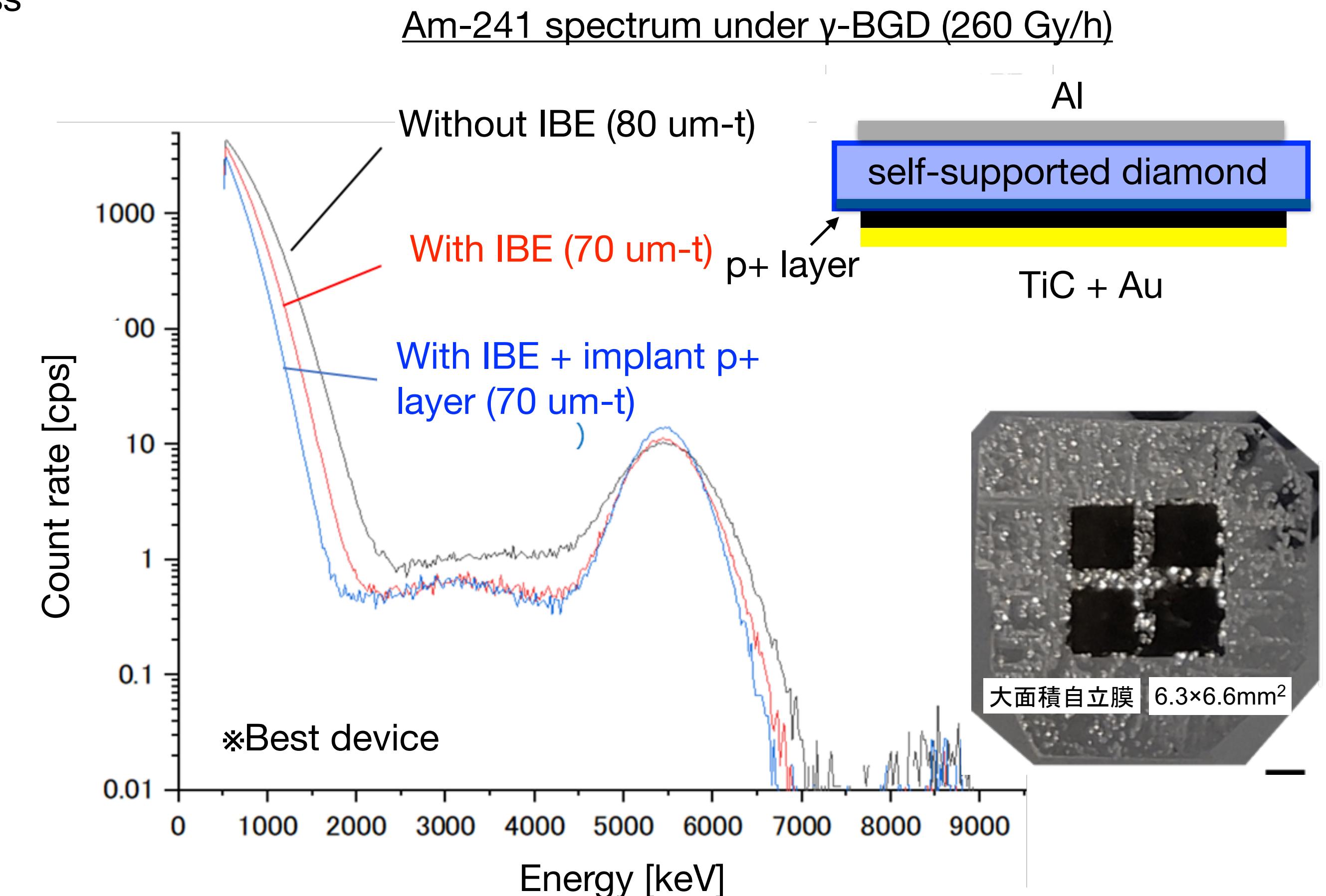
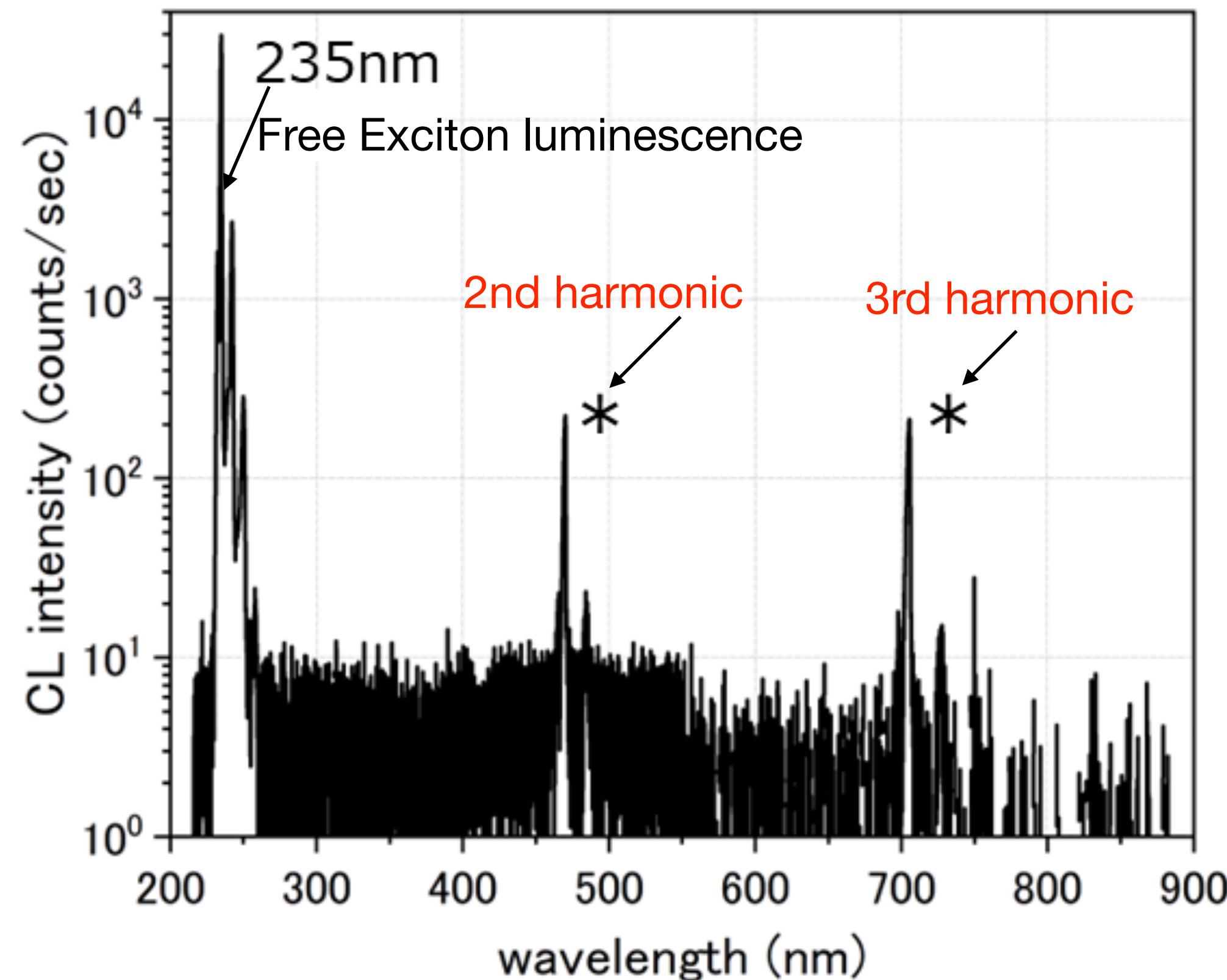
Self-supported diamond



Long process time is covered by parallel CVD machines by venture company.

Characteristics of the diamond device

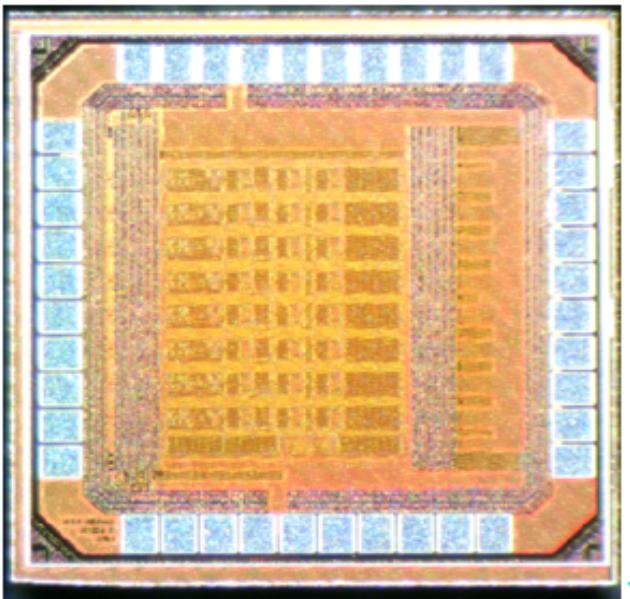
- Cathode luminescence method, free-exciton recombination line@ 235nm
- IBE (Ion Beam Etching) on 10 um surface to mitigate roughness
- Implant p+ layer on Ohmic side



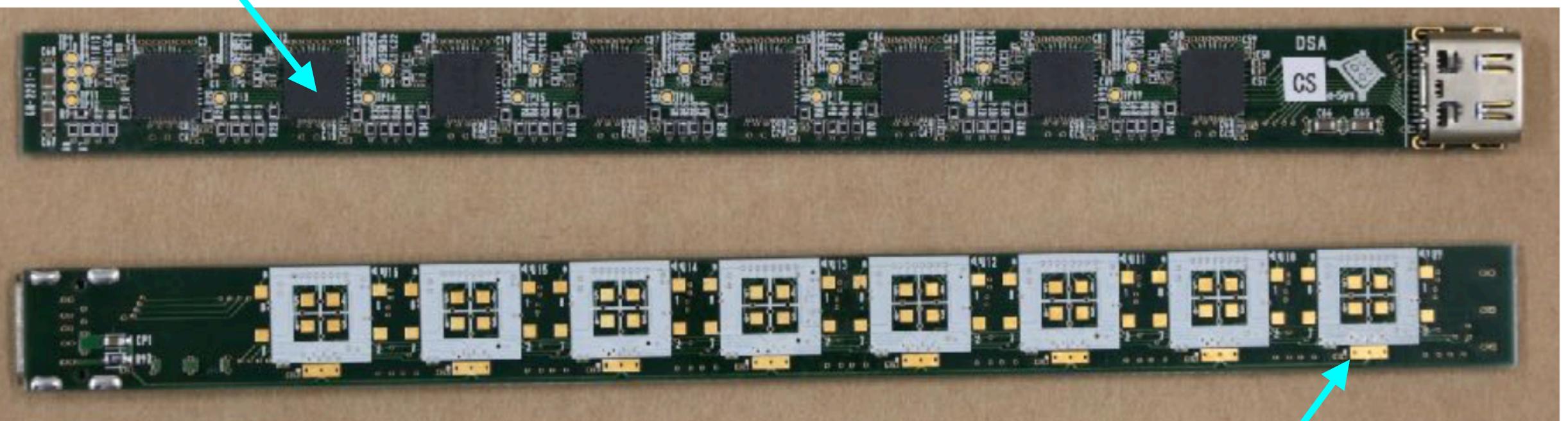
γ -rejection capability increased by IBE and p+ layer.

Analog front-ends & prototype

- TSMC 65 nm LP process, 1 mm x 1 mm
- 8 channels, CSA+CR-RC+Disc.+counter
- No ENC degradation confirmed @ 1 MGy

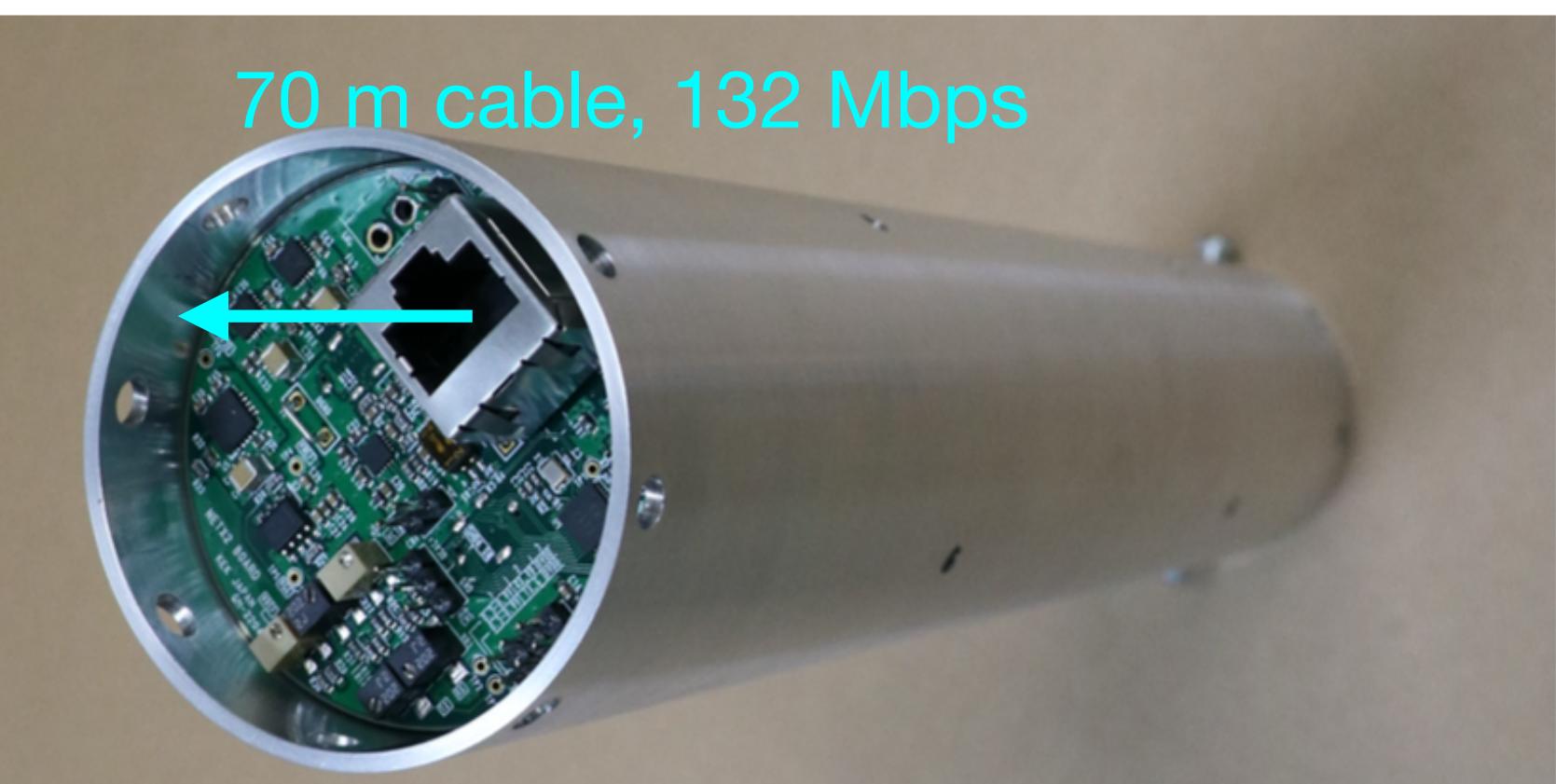
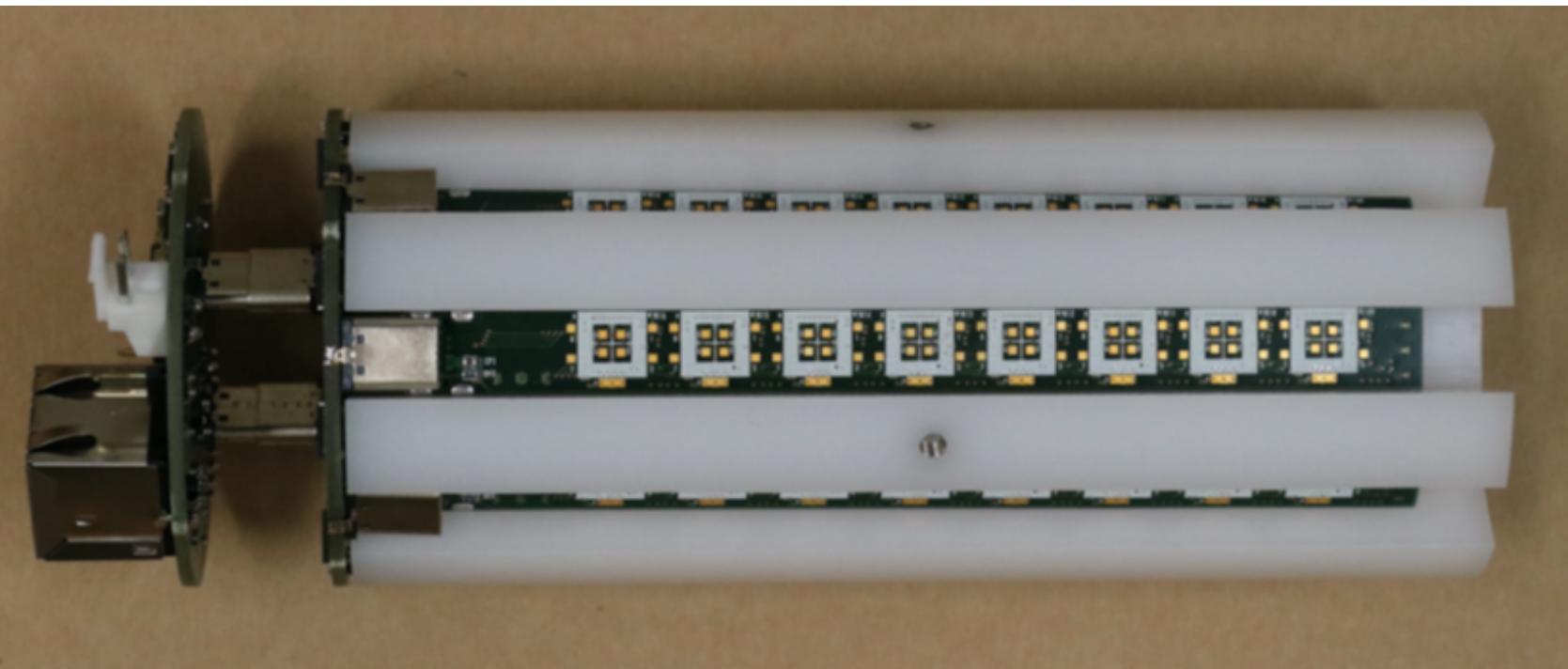


Nu-K_CSA (0.5 mW/ch)	
Type	charge sensitive
Peaking time	50nsec($t_w \sim 100$ nsec)
Noise	~1500e @ Cdet=5pF
S/N	~350@Cdet=5pF



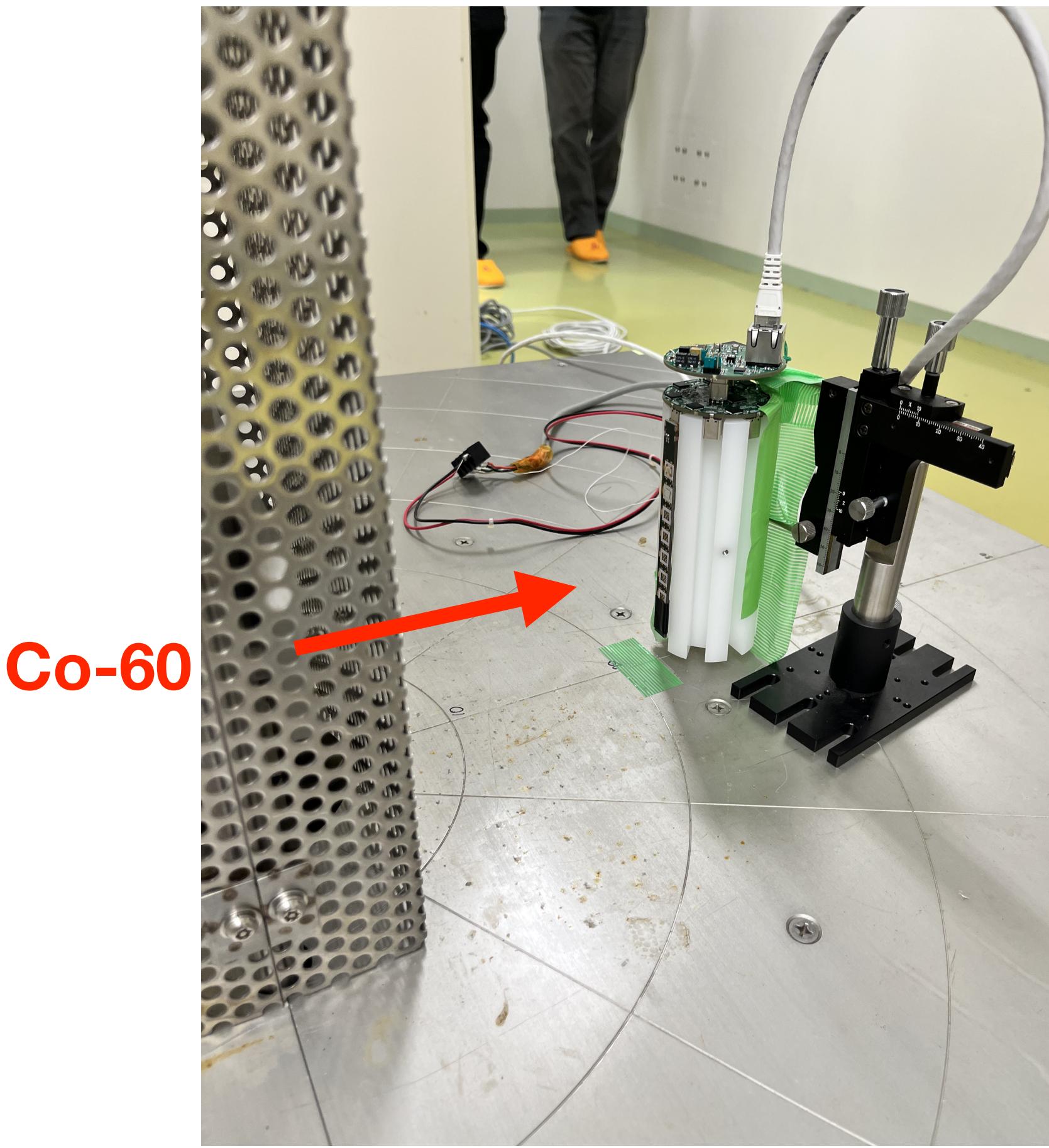
Sensor pads (4ch x 600 chips!)

Prototype of the neutron detector

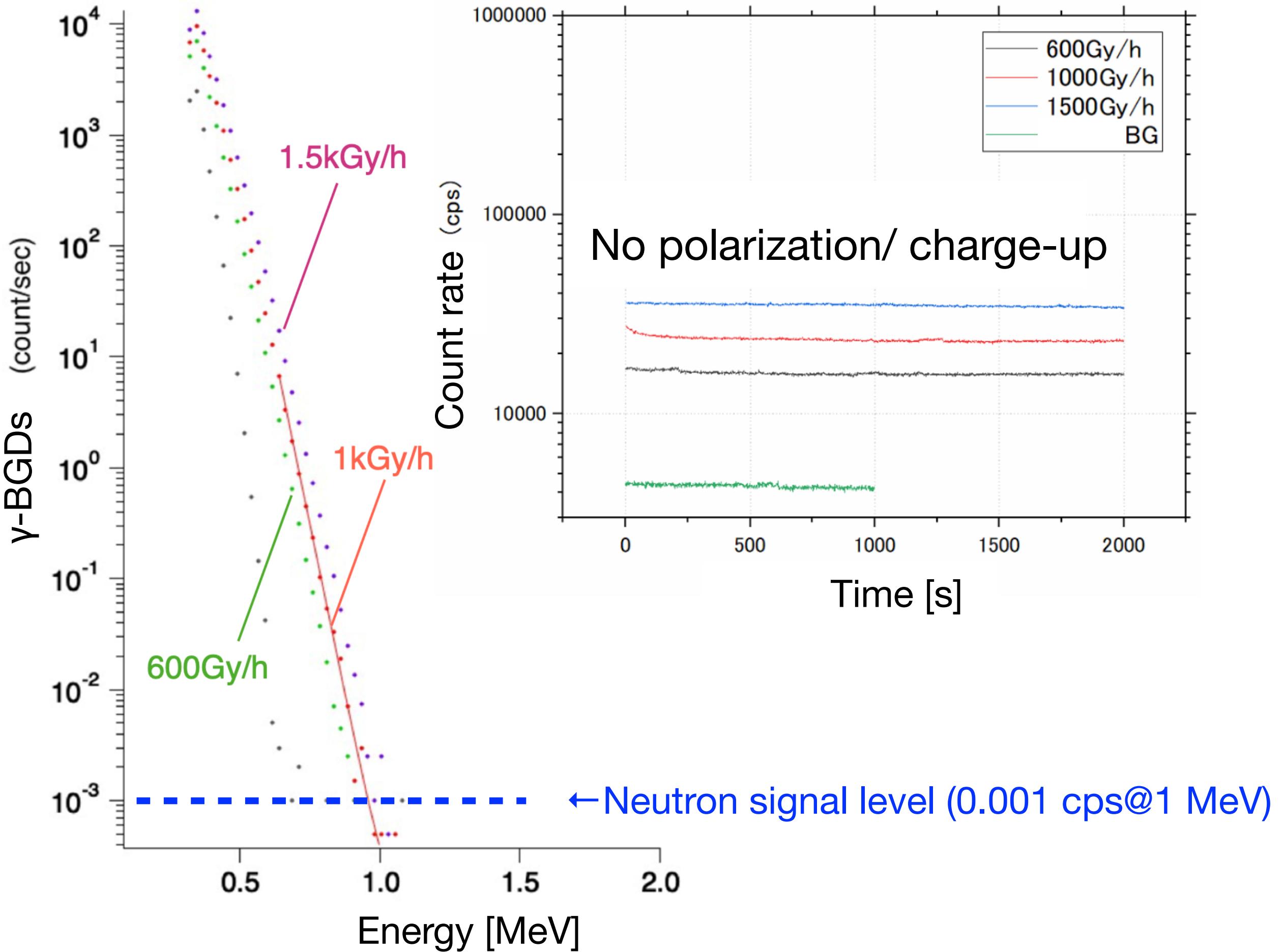


System test @ γ -facility

- Tested best device under γ -BGDs, 1 kGy/h is the requirement
- Neutron converters under preparation



γ -ray response of the AFF (CSA)



Readout system meets all requirement and we start to develop actual detector from this October.

Thank you very much for your attention.